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# **[AD4080](https://www.analog.com/AD4080)**

#### **FEATURES**

- ► High performance
	- ► Throughput: 40 MSPS, 46.25 ns conversion latency
	- ► INL: ±4 ppm (typical), ±8 ppm (maximum)
	- ► SNR/THD
		- ► 93.6 dB (typical)/-110 dB (typical) at  $f_{IN}$  = 1 kHz
		- ► 93.5 dB (typical)/-104 dB (typical) at  $f_{IN}$  = 1 MHz
	- ► Noise spectral density: −167.6 dBFS/Hz
	- ► 20-bit resolution, no missing codes
- ► Low power
	- ► 79.3 mW typical at 40 MSPS with −0.5 dBFS sine-wave input
- ► Easy Drive, fully differential Input
	- $\triangleright$  6 V p-p differential input range
	- ► Continuous signal acquisition
	- ► Linearized, 5 μA/MSPS input current
- ► Integrated, low-drift reference buffer and decoupling
- $\blacktriangleright$  Integrated V<sub>CM</sub> generation
- ► Digital features and data interface
	- ► Conversion result FIFO, 16K sample depth
	- $\blacktriangleright$  Digital averaging filter with up to 2<sup>10</sup> decimation
- ► SPI configuration
- ► Configurable data interface
	- ► Single lane, DDR, serial LVDS, 800 MBPS per lane
	- ► Dual lane, DDR, serial LVDS, 400 MBPS per lane
	- ► Single/quad lane SPI data interface
- ► Package
	- $\triangleright$  49-ball, 5 mm x 5 mm CSP\_BGA, 0.65 mm pitch
	- ► Integrated supply decoupling capacitors
- ► Operating temperature range: −40°C to +85°C

#### **APPLICATIONS**

- ► Digital imaging
- ► Cell analysis
- ► Spectroscopy
- ► Automated test equipment
- ► High speed data acquisition
- ► Digital control loops, hardware in the loop
- ► Power quality analysis
- ► Source measurement units
- ► Electron and x-ray microscopy
- ► Radar level measurement
- ► Nondestructive test
- ► Predictive maintenance and structural health

#### **Rev. A**

#### **[DOCUMENT FEEDBACK](https://form.analog.com/Form_Pages/feedback/documentfeedback.aspx?doc=AD4080.pdf&product=AD4080&rev=A) [TECHNICAL SUPPORT](http://www.analog.com/en/content/technical_support_page/fca.html)**

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# 20-Bit, 40 MSPS, Differential SAR ADC

#### **FUNCTIONAL BLOCK DIAGRAM**



*Figure 1. AD4080 Functional Block Diagram*

#### **GENERAL DESCRIPTION**

The AD4080 is a high-speed, low noise, low distortion, 20-bit, Easy Drive, successive approximation register (SAR) analog-to-digital converter (ADC). Maintaining high performance (signal-to-noise and distortion (SINAD) ratio > 90 dBFS) at signal frequencies in excess of 1 MHz enables the AD4080 to service a wide variety of precision, wide bandwidth data acquisition applications. Simplification of the input anti-alias filter design can be accomplished by applying oversampling along with the integrated digital filtering and decimation to reduce noise and lower the output data rate for applications that do not require the lowest latency of the AD4080.

The AD4080 Easy Drive features reduce both signal chain complexity and power consumption while enabling greater channel density and flexibility in companion component selection. The product input structure was designed to minimize any input dependent signal currents; therefore, reducing any converter induced settling artifacts. The continuous acquisition architecture allows settling across the entire conversion cycle, easing ADC driver settling and bandwidth requirements as compared to other high-speed data converters.

The AD4080 includes several elements that simplify data converter integration: a low drift reference buffer, low dropout (LDO) regulators to generate ADC core and digital interface supply rails, and a 16K result data first-in first out (FIFO) that can greatly reduce the load on the digital host. Additionally, critical supply and reference decoupling capacitors are integrated in the package to ensure optimum performance, simplify printed circuit board (PCB) layout, and reduce the overall solution footprint.

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# **REVISION HISTORY**



# **3/2024—Revision 0: Initial Version**

<span id="page-2-0"></span>VDD33 = 3.3 V ± 5%, VDDLDO = 1.5 V to 2.7 V, VDD11 = 1.1 V ± 5%, IOVDD = 1.1 V − 5% to 1.2 V + 5%, voltage reference input (V<sub>REFIN</sub>) = 3.0 V, sampling frequency (f $_{\rm S})$  = 40 MHz, and T<sub>A</sub> = T<sub>MIN</sub> to T<sub>MAX</sub>, unless otherwise noted.





#### *Table 1. Specifications (Continued)*



#### *Table 1. Specifications (Continued)*



# <span id="page-5-0"></span>**TIMING SPECIFICATIONS**

VDD33 = 3.3 V ± 5%, VDDLDO= 1.5 V to 2.7 V, VDD11 = 1.1 V ± 5%, IOVDD = 1.1 V - 5% to 1.2 V + 5%, V<sub>REFIN</sub> = 3.0 V, f<sub>S</sub> = 40 MHz, and T<sub>A</sub>  $T_{MIN}$  to  $T_{MAX}$  unless otherwise noted.

#### *Table 2. Timing Specifications*



#### *Table 2. Timing Specifications (Continued)*



#### <span id="page-7-0"></span>**ABSOLUTE MAXIMUM RATINGS**

#### *Table 3. Absolute Maximum Ratings*



Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

#### **THERMAL RESISTANCE**

Thermal performance is directly linked to PCB design and operating environment. Careful attention to PCB thermal design is required.

 $\theta_{JA}$  is the natural convection junction to ambient thermal resistance measured in a one cubic foot sealed enclosure.  $\theta_{\text{JC}}$  is the junction to case top thermal resistance.

#### *Table 4. Thermal Resistance*



#### **ELECTROSTATIC DISCHARGE (ESD) RATINGS**

The following ESD information is provided for handling of ESD-sensitive devices in and ESD-protected area only.

Human body model (HBM) per ANSI/ESDA/JEDEC JS-001.

Field induced charged-device model (FICDM) per ANSI/ESDA/JE-DEC JS-002.

#### **ESD Ratings for the AD4080**

#### *Table 5. AD4080, 49-Ball CSP\_BGA*



#### **ESD CAUTION**



**ESD (electrostatic discharge) sensitive device**. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

#### <span id="page-8-0"></span>**PIN CONFIGURATION AND FUNCTION DESCRIPTIONS**



*Figure 2. Pin Configuration*



#### *Table 6. Pin Function Descriptions*

#### **PIN CONFIGURATION AND FUNCTION DESCRIPTIONS**

#### *Table 6. Pin Function Descriptions (Continued)*



#### <span id="page-10-0"></span>**PIN CONFIGURATION AND FUNCTION DESCRIPTIONS**

#### *Table 6. Pin Function Descriptions (Continued)*



<sup>1</sup> AI is analog input, AO is analog output, DI is digital input; DI/O is digital input and output, DO is digital output, and P is power.

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*Figure 4. FFT 40 MSPS, fIN = 1 MHz, −1.0 dBFS*



*Figure 5. SNR vs. Input Signal Frequency (Amplitude = −0.5 dBFS, −1 dBFS, −3 dBFS, −6 dBFS, −10 dBFS, and −12 dBFS)*



*Figure 6. THD vs. Input Signal Frequency (Amplitude = −0.5 dBFS, −1 dBFS, −3 dBFS, −6 dBFS, −10 dBFS, and −12 dBFS)*







*Figure 8. Sinc5 + Compensation Filter, Pass-Band Flatness*

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*Figure 9. Sinc1 Filter Response, f<sup>S</sup> = 40 MHz (DEC x Means Decimate By)*



*Figure 10. Sinc5 Filter Response, f<sup>S</sup> = 40 MHz*



*Figure 11. Sinc5 + Compensation Filter Response, f<sub>S</sub> = 40 MHz* 



*Figure 12. SNR vs. Total Decimation Rate, Sinc1*



*Figure 13. SNR vs. Total Decimation Rate, Sinc5*



*Figure 14. SNR vs. Total Decimation Rate, Sinc5 + Compensation*

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*Figure 15. INL vs. Code for Various Temperatures, 40 MSPS*







*Figure 17. Histogram of Codes, Sinc1, No Filter, Decimate 2×, Decimate 4× … Decimate 1024×*



*Figure 18. Histogram of Codes, Sinc5, No Filter, Decimate 2×, Decimate 4× ...Decimate 256×*



*Figure 19. Histogram of Codes, Sinc5 + Compensation, No Filter, Decimate 2×, Decimate 4× … Decimate 512×*



*Figure 20. Offset Voltage Histogram*

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*Figure 23. PSRR vs. Frequency*







*Figure 25. CMO Voltage Variation vs. Load Resistance*



*Figure 26. Dynamic REFIN Current vs. Temperature*

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*Figure 27. Total Power vs. Sampling Frequency*



*Figure 28. Total Power at 40 MSPS vs. Temperature*



*Figure 29. Total Power vs. Temperature in Sleep and Standby Modes*



*Figure 30. AC CMMR vs. Input Frequency*

# <span id="page-16-0"></span>**Integral Nonlinearity Error (INL)**

INL refers to the deviation of each output code from a line drawn between points at negative full scale and positive full scale. The negative full-scale reference is defined by an input level equivalent to ½ LSB prior to the first code transition. The positive full-scale reference is defined as an input level that is 1½ LSB beyond the last code transition. The deviation is measured from the center of each code relative to the straight line.

# **Differential Nonlinearity Error (DNL)**

In an ideal ADC, code transitions occur at 1 LSB intervals. DNL is a measure of the maximum deviation of any code from the ideal code width. DNL is specified in terms of resolution for which no missing codes are guaranteed.

# **Zero Error**

Zero error is the difference between the ideal midscale voltage, 0 V, and the applied voltage producing the midscale output code, 0 LSB.

# **Gain Error**

Gain error is specified as the difference in the slope of the ADC transfer characteristic vs. that of an ideal converter. In an ideal data converter, the first code transition (100 … 00 to 100 … 01) occurs ½ LSB more than the nominal negative full-scale input (−2.999997 V for a ±3.0 V range at 20 bits) and the last code transition (011  $\ldots$  10 to 011  $\ldots$  11) occurs 1 $\frac{1}{2}$  LSB less than the nominal positive full-scale input  $(+2.999991 \text{ V}$  for a  $\pm 3.0 \text{ V}$  range at 20 bits).

# **Signal-to-Noise Ratio (SNR)**

SNR is the computed ratio of the fundamental signal amplitude measured in RMS volts and the root sum of squares of all other spectral components in the Nyquist bandwidth ( $f < f<sub>S</sub>/2$ ) excluding harmonics and DC components. The computed value of SNR is converted into a logarithmic scale and expressed in decibels (dB).

# **Signal-to-Noise-and-Distortion (SINAD) Ratio**

SINAD is the computed ratio of the fundamental signal amplitude measured in RMS volts and the root sum of squares of all other spectral components in the Nyquist bandwidth  $(f < f_S/2)$  including harmonic components but excluding the DC component. The computed value of SINAD is converted into a logarithmic scale and expressed in decibels (dB).

# **Total Harmonic Distortion (THD)**

THD is the ratio of RMS sum of the amplitudes of the first five harmonic components to the RMS amplitude of a full-scale input signal expressed in decibels (dB).

# **Spurious-Free Dynamic Range (SFDR)**

SFDR is the ratio between the RMS amplitude of the input signal and the peak spurious signal amplitude, expressed in decibels (dB).

# **Intermodulation Distortion**

With inputs consisting of sine waves at two frequencies,  $f_A$  and  $f_{B}$ , any active device with nonlinearities creates distortion products at sum and difference frequencies of  $m \times f_A$  and  $n \times f_B$ , where  $m, n = 0, 1, 2, 3,$  and so on. Intermodulation distortion terms are those for which neither m nor n are equal to 0. For example, the second-order terms include ( $f_A + f_B$ ) and ( $f_A - f_B$ ), and the third-order terms include ( $2f_A + f_B$ ),  $(2f_A - f_B)$ ,  $(f_A + 2f_B)$ , and  $(f_A - f_B)$  $2f_B$ ).

The AD4080 is tested where two input frequencies near the top end of the input bandwidth are used. In this case, the second-order terms are usually distanced in frequency from the original sine waves, and the third-order terms are usually at a frequency close to the input frequencies. As a result, the second-order and third-order terms are specified separately. The calculation of the intermodulation distortion is as per the THD specification, where it is the ratio of the RMS sum of the individual distortion products to the RMS amplitude of the sum of the fundamentals, expressed in decibels.

# **Power Supply Rejection Ratio (PSRR)**

PSRR is a measure of the sensitivity of the ADC to variations in the specified power supply rail vs. frequency. PSRR is computed as the ratio of the observed change in the output code in RMS volts to the RMS magnitude of the perturbing signal coupled to the supply. The resulting ratio is reported in decibels (dB).

#### <span id="page-17-0"></span>**PRODUCT OVERVIEW**

The AD4080 is a high-speed, low noise, low distortion, 20-bit, Easy Drive, SAR ADC. The device is capable of conversion rates up to 40 MSPS, with 46.25 ns result output latency. The parametric performance, bandwidth, and throughput make this product ideal for a variety of high-speed, data acquisition applications. Innovations in the AD4080 product design enable both complexity reduction and component flexibility in the design of data acquisition signal chains.

The converter architecture enables continuous acquisition of the input signal throughout the entire conversion period,  $t_{\text{CONV}}$ , reducing the input signal conditioning bandwidth required to settle to the specified resolution.

The design incorporates circuitry to reduce the nonlinear input current associated with the charge kickback typical of a switched capacitor SAR input.

Conversion result access occurs via either a multilane LVDS port operating at clock rates up to 400 MHz or via a multioutput SPI operating at clock rates up to 50 MHz.

The LVDS interface is compatible with differential signaling standards between 1.2 V and 2.5 V. To maximize throughput the previous conversion results can be read through the entirety of the conversion period as long as the CNV+ edge and CLK+ rising edges are aligned. The LVDS interface is described in detail in the [LVDS Data](#page-43-0) [Interface Configuration](#page-43-0) section.

The single or quad lane SPI data interface is also available for CMOS level interfacing. When configured, this interface is used to access conversion results stored in the on-chip FIFO. FIFO operation is explained in the [Result FIFO](#page-54-0) section.

# **CONVERTER OPERATION**

A conventional SAR ADC typically operates in two phases; an acquisition phase, whereby the analog input voltage is acquired on the analog input pins, followed by a conversion phase, initiated by a conversion start signal. During the conversion phase the sampled analog input voltage is converted to a digital conversion result. In a single ADC, this is typically performed by converting the voltage from one sampling circuit. In the case of the AD4080, Figure 31 details the unique feature of this converter, whereby the analog input is connected to two sampling circuits, and the input is sampled by each one in sequence. To a user, this requires no additional control or configuration, and as such, is completely transparent in usage.



*Figure 31. Simplified Representation of the AD4080 SAR ADC*

The AD4080 converter seamlessly sequences back and forth from one sampler to the other, meaning that one sampler is in acquisition mode while the voltage sampled on the other is being converted. Figure 32 shows that the AD4080 timing is contrasted against a conventional SAR ADC, where it switches between sequential conversion and the acquisition phase leads to a reduced amount of time for the input signal acquisition and settling. As sampling rates increase (and therefore cycle times reduce), it is important to maintain longer acquisition times to enable settling, particularly to the higher levels of precision offered by the AD4080. Further details on the benefits of reducing driver and noise bandwidths are described in the [Easy Drive Analog Inputs s](#page-18-0)ection.



*Figure 32. Conversion Cycle Compared to Conventional SAR*

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# <span id="page-18-0"></span>**TRANSFER FUNCTION**

The AD4080 digitizes the full-scale difference voltage of  $2 \times V_{REFIN}$ into 2<sup>20</sup> levels, resulting in an LSB size of 5.72  $\mu$ V with V<sub>REFIN</sub> = 3.0 V. Note that 1 LSB at 20 bits is approximately 0.95 ppm.

Table 7 summarizes the mapping of input voltages to differential output codes.



*Figure 33. ADC Ideal Transfer Function for the Differential Output Codes (FSR Is Full-Scale Range)*





# **EASY DRIVE ANALOG INPUTS**

The AD4080 signal input consists of a fully differential input pair (IN+ and IN−), each connected to the input sampling network (series resistance  $(R<sub>S</sub>)$  and sampling capacitance  $(C<sub>S</sub>)$ ) and a pair of auxiliary inputs (AUXIN+ and AUXIN−) that provide a reference to the sampling network linearization circuits. An equivalent circuit model of the analog input is presented in Figure 34.



*Figure 34. Equivalent Analog Input Circuit Model*

In this model, the input sampling network was simplified to consist of two ideal switches,  $R<sub>S</sub>$  and  $C<sub>S</sub>$ , for the ADC in acquisition mode. The typical values for C<sub>S</sub> is 23.5 pF and R<sub>S</sub> is 26  $\Omega$ .

The parasitic capacitance related to the pin connection,  $C_{\text{PIN}}$ , is modeled as a shunt capacitor between the pin and device ground terminal (GND). The capacitance includes parasitic capacitance formed from the physical interface, routing in the package substrate and the device input protection circuits. The  $C_{\text{PIN}}$  value is typically 4.5 pF. The input protection circuit for the AD4080 is modeled as diode clamps to the GND and VDD33 supply rails.

The external low-pass filters (LPFs) constructed from  $R_{FII}$ <sub>TIN</sub> and  $C_{FILTING}$  and  $R_{FILTAUX}$  and  $C_{FILTAUX}$  are band-limiting filters for the primary and auxiliary paths, respectively.

The combination of  $R_{FILTIN}$  and  $C_{FILTIN}$  are often referred to as anti-aliasing filters because these filters do introduce a single-pole filter in the analog input signal path. However, the function of  $C_{\text{FII TIN}}$ is more complex and must be carefully considered. Conversion through a SAR involves sampling the voltage from an internal capacitor, represented by  $C_S$  in the Figure 34, which typically occurs in two phases in time  $\phi_1$  and  $\phi_2$ . During the first phase, the  $\phi_1$ switches are closed, the  $\phi_2$  switches are opened, and the sampling capacitors  $(C<sub>S</sub>)$  are charged to the analog input voltages present at IN+ and IN−. During the second phase, the ϕ<sup>1</sup> switches are opened, the  $\phi_2$  are closed, and the ADC converts the voltage onto C<sub>S</sub>.

Another short time phase exists, where the  $C_S$  charge is reset after the conversion is complete. This process repeats for each new ADC conversion. The transfer of charge from the ADC analog input pins to  $C_{\rm S}$ , due to the closing of the switches in each conversion cycle, creates a demand at the analog input pin. It is important to ensure that the voltage presented at the input pin is undisturbed by the internal ADC activity so that the voltage can be converted with the highest accuracy. Each new conversion presents a disturbance, or kick, at the input. The faster the ADC conversion rate is, the more frequent the occurrence of these kicks. An ADC driver is used to ensure that the input voltage, disturbed by the kick at each sampling instance, is fully settled to the required ADC resolution prior to the next sample being acquired. The ADC driver amplifier must have a wide enough output bandwidth to settle the voltage in time for each sample, which creates a signal chain design constraint to

ensure that there is enough time to settle to the required voltage accuracy (or ADC resolution). For this reason, a fast ADC requires a wide bandwidth driver. For high resolution ADC converters, low signal chain noise is required to obtain high resolution. A wider bandwidth can result in more noise coming through the signal chain to the ADC, which can present a significant signal chain design challenge for a conventional SAR ADC. However, the AD4080 includes some unique Easy Drive features that simplify these aspects of signal chain design.

One such AD4080 feature is continuous signal acquisition. Due to its unique design, that the  $t_{AOC}$  is equal to the  $t_{CYC}$  of the ADC, resulting in the AD4080 being in signal acquisition mode for the full duration of each ADC conversion. The input voltage has 100% of the  $t_{\rm CYC}$  conversion time to settle the input voltage before the next conversion, whereas a conventional ADC may need to settle in 60% of this time. More settling time results in less bandwidth required by the driver, which generally, bears a lower power requirement. In addition, because the external filters ( $R_{\text{FII TIN}}$ ) and  $C_{FII\;TIN}$ ) must be designed with enough bandwidth for the driver to settle the input voltage, the additional settling time results in a lower cut-off. Because of this lower cut-off, more of the signal chain noise can be filtered at the inputs with these external filters.

Another Easy Drive feature is its highly linearized analog input current. With this feature, the AD4080 presents a less challenging load to a driver amplifier and reduces any potential distortion from a driver that can occur when presented with a nonlinear input current. Figure 35 shows the typical input currents into both the differential signal pair (IN+ and IN−) and auxiliary inputs (AUXIN+ and AUXIN−).



*Figure 35. Typical Input Current vs. Differential Input Voltage*

To design the external input filter, it is usual to calculate how many time constants (K) are needed for the required resolution.



For n-bit converter, 1ppm can be calculated using the following formula 1ppm =  $2<sup>n</sup>$  /1000000. To calculate the time constant from the natural log of the required setting resolution, for example, if settling to within 1 ppm of 20 bits ( $n = 20$ ) of the resolution required, 1ppm would represent  $1.048576$  LSBs (or  $2<sup>n</sup>$ /1000000) and we would use the following equation:

 $K = \ln(2^{n}/1.048576) = 13.86$  time constants (1)

When considering a conventional ADC, as described in the [Con](#page-17-0)[verter Operation](#page-17-0) section, where the acquisition time is only 60% of the ADC conversion cycle, there is less time available for settling. For such an ADC sampling at 40 MSPS, the driver must settle within 25 ns × 0.6 or 15 ns, and settling of the input voltage within 1 ppm also requires a time constant tau (τ) of 15 ns  $\div K = 1.082$  ns or a bandwidth of  $1/(2 \times \pi \times \tau) = 147$  MHz.

However, with the Easy Drive features of the AD4080, the result is an acquisition time of 100% of the conversion cycle, which indicates only 13.86 time constants to settle within 1 ppm of 20 bits resolution. However, additionally, the low analog input current of the AD4080 and the internal methods that reduce any kick back to the driver (as charge transfers from the analog input to the internal sampling capacitors at the sampling instance) reduce the required number of time constants by 9.5%. Therefore, for the 20-bit settling example, the required number of time constants (K) reduces from 13.86 to 12.55 without impact on settling or distortion.

These Easy Drive features significantly reduce the required driver bandwidth required to settle. For example, at 40 MSPS, settling of the input voltage within 1 ppm requires a time constant tau (τ) of 25 ns ÷ K = 1.992 ns, or a bandwidth of  $1/(2 \times \pi \times \tau)$  = 80 MHz. This significant reduction in the required bandwidth allows use of lower power, lower bandwidth drivers and the design of a lower bandwidth input filter to remove more driver or signal chain noise. Table 8 suggests some filter values for use with the AD4080 in some example use case conditions.

Another Easy Drive feature, as can be seen in the [Figure 34](#page-18-0), is the auxiliary signal input path. This path feeds the analog input signal to an internal linearization block, and this block feeds a correction signal to the sampled voltage. Recommended values are given in Table 8. The filter on the auxiliary inputs is set for the same bandwidth as the analog input, and  $R_{FII}$ <sub>TAUX</sub> must be set at 4  $\times$  $R_{FILTING}$ . The recommended filter configuration is to use a differential  $C_{FILTIN}$  capacitor; therefore, calculate the components as  $T = R_{FILTIN}$  $\times$  2  $\times$  C<sub>FII TIN</sub>.

Note that the minimum R<sub>FILTIN</sub> must be 15 Ω, and that R<sub>FILTAUX</sub> can be set from a minimum of 5  $\Omega$  up to 4 × R<sub>FILTIN</sub>.



*Table 8. Recommended Input Filter Configurations (Continued)*



#### <span id="page-21-0"></span>**REFERENCE BUFFER AND COMMON-MODE OUTPUT**

The AD4080 integrates a charge reservoir capacitor  $(C_{RFF})$  and a low-drift reference buffer at the reference input pin (REFIN), eliminating the need for dedicated external components and enabling multiple AD4080 devices to share a single voltage reference.

The integrated capacitor ( $C_{RFF}$ ) has a capacitance of 9.4  $\mu$ F  $\pm$  20%, and it is constructed from commercially available, multilayer, high dielectric (X6S), ceramic capacitors.  $C_{RFF}$  serves as the primary charge reservoir for the data converter. Integrated, in-package components, such as  $C_{RFF}$ , minimize the overall solution area, mitigate potential performance errors introduced by factors like component selection, placement and routing challenges, and in general, reduce the engineering effort to first design success.

Additional external capacitance  $(C_{RSV})$  can be placed across the REFIN and REFGND pins for improved charge capacity and noise rejection as required. As with all precision circuits, the placement of the external reference capacitors must be as close to the device pins as possible on the same side of the PCB. The routing between the capacitor and device pins must minimize the series impedance in each routing path.



*Figure 36. REFIN and CMO Internal Equivalent Circuit and Typical Application*

The AD4080 internally generates a common-mode reference voltage of one-half of  $V_{REFIN}$ , which is output through the CMO pin. The absolute error in the CMO output voltage is guaranteed to be less than ±20 mV. The CMO output is used to set the common-mode output voltage of the analog front-end stage driving the AD4080 inputs, ensuring the AD4080 common-mode input requirement is satisfied. The CMO output must be filtered with a RC LPF to limit the total output noise as illustrated in Figure 36 (see  $R_{CMF}$  and  $C_{CMF}$ ).

The output is generated using a resistive divider connected to the reference buffer output. The resulting output impedance at the CMO pin is typically 700  $Ω$ . Due to the limited drive capability at the CMO pin, the external load must be carefully considered to avoid excessive start-up times or absolute errors. The CMO output may be directly connected to a high impedance common-mode input of a fully differential amplifier driving the AD4080, assuming the

charging time for the preceding noise limiting filter does not impact the start-up time required for the application. In general, consider CMO buffering for the following situations:

- ► The VDD33 power rail of the AD4080 is frequently cycled.
- ► Short start-up settling times are required.
- ► If the external load on CMO exceeds 30  $\mu$ A (R<sub>L</sub> < 45 kΩ). See [Figure 25](#page-14-0) for the typical load regulation information.

# **POWER SUPPLIES**

The power requirements for the AD4080 are distributed across a minimum of three supply domains including a 3.3 V analog circuit domain (VDD33), a 1.1 V core supply (VDD11), and a 1.1 V domain for the digital interface (IOVDD). An optional fourth supply rail (VDDLDO) can be used to supply power to two integrated voltage regulator used to internally power the 1.1 V core (VDD11) and interface (IOVDD) rails. Each of these two regulators can be independently turned off by software. For all details and design considerations when using the internal voltage regulators, see the [Internally Regulated Supply Configuration](#page-22-0) section. On the other hand, for applications that will not use internal regulators see the [Externally Generated Supply Configuration](#page-22-0) section for further details.

Power for the VDD33 supply rail must be supplied from an external source and must only be applied once power is supplied to the 1.1 V supply rails as described in the [Power Supply Sequence](#page-23-0) section.



*Figure 37. Typical Regulator Start-Up Transient, Converter Idle*

All supply domains are internally decoupled using multilayer, high dielectric, ceramic capacitors (X6S), eliminating the need of external decoupling capacitors. However, care must be taken to understand the bulk decoupling requirements for other components in the design which share the same supply. Integrated supply decoupling capacitors in the AD4080 are listed [Table 6](#page-8-0) as well as in Table 9.





#### <span id="page-22-0"></span>*Table 9. Integrated Supply Decoupling Summary (Continued)*



#### **INTERNALLY REGULATED SUPPLY CONFIGURATION**

The AD4080 includes two internal LDO regulators, one to generate the 1.1 V VDD11 supply rail and another to internally generate the 1.1V IOVDD supply rail. Upon power on or reset of the AD4080 registers, both regulators automatically power up when an external voltage source in the range of 1.4 V to 2.7 V is applied to the VDDLDO pin. The regulators are designed to supply the internal load requirement of the AD4080; therefore, no external loading is permitted. Noted that, as described in the [Power Saving Operating](#page-24-0) [Modes](#page-24-0) section, IOVDD is disabled in both power saving modes.

The required connectivity when using the internal regulators is illustrated in Figure 38. As shown in Figure 38, the VDD11 pins (A1, A2, and A3) must be shorted together. It is recommended that a thick trace or polygon on the device side of the PCB be used to implement this connection in the physical design to minimize routing impedance. The VDD33 rail is supplied with an external 3.3 V supply. This supply can be removed when using power saving modes. When this supply is removed, only analog circuity is held in reset, and the configuration register content remains unaffected. Refer to the [Table 1](#page-2-0) section for the applicable input voltage tolerance for each supply rail.



*Figure 38. Internally Regulated (1.1 V) Supply Configuration*

The internally regulated configuration is ideal for use in area constrained applications where the ability to eliminate external regulators is advantageous. However, noted that, in this configuration, the internal supply regulation introduces additional power dissipation.

#### **EXTERNALLY GENERATED SUPPLY CONFIGURATION**

In system using externally generated supplies VDDLDO must be left unconnected. With VDDLDO unconnected both the internal LDO powering VDD11 and the internal LDO powering IOVDDD are automatically disabled. VDD11 must be connected to an externally generated 1.1V supply rail and IOVDD should be connected to an externally generated 1.1V to 1.2V supply rail. It should be noted that if VDD11 is not present the part will be held in a POR state and all AD4080 registers reset to their default state the after the

supply has been reestablished. More details on the POR circuitry can be found in the Power-On Reset (POR) Monitor section. The VDD33 rail is supplied with an external 3.3 V supply. The VDD33 supply can be removed to further reduce power in the [Power](#page-24-0) [Saving Operating Modes,](#page-24-0) only analog circuity is in held in reset, and the register content remains unaffected. Refer to [Table 1](#page-2-0) for the applicable input voltage tolerance for each supply rail.

As illustrated in the example of Figure 39, external voltage sources are applied to VDD11 and IOVDD pins.



*Figure 39. Externally Sourced Supply Configuration*

# **POWER-ON RESET (POR) MONITOR**

The AD4080 power supply monitoring circuits inhibit the converter functions and reset the configuration memory when supply conditions are outside the specified operating limits. This function ensures each device is in a deterministic state after power-up. The power-on function is constructed from two independent voltage monitors, the first measuring the core 1.1 V supply and a second measuring the voltage at the reference input (REFIN). Each monitor has its own comparator output that is used to decouple the analog and digital block resets as shown in Figure 40.



*Figure 40. Simplified Diagram of POR Circuit*

The core VDD (1.1 V) supply monitor compares the VDD11 supply voltage against a preset threshold of 0.93 V. If the supply voltage falls to less than this threshold, a reset signal, POR D, asserts. The digital logic reset signal, DIG RESET, is defined as the logical combination of the POR D signal and (logical AND) the compliment of the SPI software reset function. When either the POR D signal (VDD11 < 0.93 V) or the SW RESET signal is asserted, the internal digital circuitry is held in reset. When cleared, the contents of the configuration registers are restored to the factory default settings.

<span id="page-23-0"></span>The reference monitor compares the input voltage at the reference input pin, REFIN, against a preset threshold of 2.7 V. As illustrated in [Figure 40](#page-22-0), power for the reference monitor circuit is supplied from the VDD33 supply. For correct operation of the monitor circuit, the VDD33 supply must be applied to the AD4080 within the specified tolerance of  $3.3 \text{ V} \pm 5\%$  before the reference source is enabled. Assuming the device is operating within the specified supply conditions, a reference voltage less than 2.7 V results in the assertion of an internal reset signal, POR A. The POR A signal and (logical AND) the DIG\_RESET signal are combined to produce a reset (ANA\_RESET) for the analog circuit blocks including the ADC core, ADC timer, reference buffer, etc. If this reset signal is asserted, the analog blocks are placed in an inactive state, and the converter functionality is disabled. This event is indicated with a value of 1 in the POR ANA FLAG bit from the [Device Status Register](#page-81-0) (Address 0x14). The state of the event detection is persistent until a Logic 1 is written to the POR ANA\_FLAG bit to clear the detection state.

#### **POWER SUPPLY SEQUENCE**

Table 10 specifies the recommended supply sequences for both internal and external generation of 1.1 V supply rails (IOVDD and VDD11). Both methods are shown in Figure 41 and [Figure 42](#page-24-0), where highlighted in blue are the supplies that must be provided to the AD4080, including the REFIN voltage. In both cases, the AD4080 requires that the supplies are applied in ascending voltage order. The design must also ensure that voltage is applied at the analog inputs (IN+ and IN−) and reference input (REFIN) concurrently with or immediately following the VDD33 supply. As described in the [Power-On Reset \(POR\) Monitor](#page-22-0) section, the voltage at the reference input pin must only be applied once VDD33 is within the

specified supply tolerance to avoid undesired behavior. Therefore, if the selected voltage reference does not provide an enable pin, it is strongly recommended to design the reference circuit to power up after VDD33.

The configuration SPI inputs,  $\overline{CS}$ , SCLK, and SDI, are protected with clamps to the VDD33 supply rail to allow the inputs to swing more than IOVDD. As a consequence of this architectural decision, it is necessary to drive the SPI inputs to ground or to otherwise leave the inputs floating until VDD33 is greater than IOVDD − 0.3 V. Alternatively, the VDD33 source can be connected to the device using a series power switch, like the [ADP199,](https://www.analog.com/adp199) configured so that the switch is open when the source is less than IOVDD − 0.3 V, eliminating the parasitic current path through the digital inputs to VDD33.

#### *Table 10. Recommended Supply Sequence*



To power down the application circuit, the power-up sequence specified in Table 10 should be reversed.



*Figure 41. Power Supply Sequence, Internally Generated IOVDD, VDD11*

<span id="page-24-0"></span>

*Figure 42. Power Supply Sequence, Externally Generated IOVDD, VDD11*

# **POWER SAVING OPERATING MODES**

The operating mode of AD4080 is controlled by the OPERAT-ING\_MODES bits in the [Device Configuration Register](#page-74-0) (Address  $0x0\overline{2}$ ). On power up and after reset, the default is normal mode (OPERATING\_MODES = 00). [Table 11](#page-25-0) describes all operating modes, and Figure 43 depicts the allowed transitions between these modes. Note that direct transitions between the two power saving modes (standby mode and sleep mode) are not permitted.

It is important to stop all conversion and data interface clocking before configuring the power mode.

When in either standby mode or sleep mode, the VDD33 supply can be removed to reduce power consumption. This supply must be re-established prior to issuing the SPI configuration interface command to exit either power saving mode.



*Figure 43. Operating Mode Transitions*

Transitioning from normal mode to either of the two power saving modes is achieved by writing the required value to the OPERAT-ING\_MODES bits in the [Device Configuration Register.](#page-74-0) Waking up (that is, transitioning back to normal mode) is achieved in a similar way because the SPI configuration interface operation is not affected by any of the power saving modes (see the [SPI Config](#page-31-0)[uration Interface](#page-31-0) section). Standby mode can be selected to save power, in the case where the user wants to quickly return to normal conversions. Sleep mode is a lower power state where returning to

normal mode takes longer. Both standby and sleep mode can be particularly useful when used with the result FIFO (see the [Result](#page-54-0) [FIFO](#page-54-0) section), whereby previously stored conversion data can be accessed from the FIFO while it is still in the selected power saving mode.

To reduce power consumption in both standby and sleep mode, the internal IOVDD LDO regulator is powered down. If the user is not externally supplying IOVDD, all IOVDD domain inputs and outputs are disabled (all GPIOx and all LVDS data interface (see the [LVDS Data Interface](#page-43-0) section) and SPI data interface (see the [SPI Data Interface](#page-49-0) section) signals are disabled). In this specific condition, it is still possible to write to the AD4080 SPI configuration to issue a command to return to normal mode by writing to the OPERATING\_MODES bits in the device configuration register (see the [Device Configuration Register](#page-74-0) section) or to issue a software reset (see the [Software Reset](#page-26-0) section). As GPIOx is disabled, it is not possible to perform any read activity on the SPI configuration interface bus.

When IOVDD is externally supplied, and the device is put into standby or sleep mode, the LVDS data interface is disabled; however, all GPIOx, SPI data interface, and SPI configuration interface pins remain enabled and unaffected. While power is supplied externally to IOVDD within its specified range, previously acquired data stored in the result FIFO can be access in either standby or sleep mode.

[Table 11](#page-25-0) also indicates the wake-up times associated with each of the modes. Wake-up time from sleep mode is significantly higher than that of standby mode because time must be allowed for the internal reference and common-mode buffers to re-enable and to replenish charge to the internal capacitors. When returning to normal mode, the specified wake-up time must be satisfied before applying the first conversion start pulse. This specified time is the time it takes from when the SPI command to exit the selected power saving mode is written to the device configuration register

<span id="page-25-0"></span>(see the [Device Configuration Register](#page-74-0) section) to update the OPERATING\_MODES bits.

For the lowest power consumption in any of the power saving operating modes, the LVDS\_SELF\_CLK\_MODE must be enabled

#### *Table 11. Power Saving Operating Modes*

in the ADC Data Interface Configuration B register (see the [ADC](#page-83-0) [Data Interface Configuration B Register](#page-83-0) section) to power down the LVDS DCO transmitter.



#### <span id="page-26-0"></span>**SOFTWARE RESET**

This reset method must only be used once the AD4080 is in an idle state, where conversions are not being clocked, and any existing conversion is completed.

A software reset is achieved by issuing the following two writes to the Interface Configuration A register (see the [Interface Configura](#page-73-0)[tion A Register](#page-73-0) section, Address 0x00):

- **1.** Set SW\_RESET and SW\_RESETX bits to 1 by writing 0x81 to the register.
- **2.** Then, issue another write command that sets either or both of those bits to 0.

This action returns any previously configured registers to their default settings, except for the ADDR\_ASCENSION bit from the Interface Configuration A register, which keeps its previous value. The contents of the FIFO, if any, are also not affected by the software reset. The ADDR\_ASCENSION bit and FIFO data only return to their default settings after a hardware reset or a full power-up happens.

#### <span id="page-27-0"></span>**TYPICAL APPLICATIONS DIAGRAMS**



*Figure 44. AD4080 Typical Applications Diagram, Fully Differential Amplifier*



*Figure 45. AD4080 Typical Applications Diagram, Single Op-Amp Drivers*

#### <span id="page-28-0"></span>**ANALOG FRONT END DESIGN**

#### **Driver Amplifier Choice**

*Table 12. Driver Amplifier Selection Table*

As described in the [Easy Drive Analog Inputs](#page-18-0) section, the AD4080 has a number of unique features that opens this ADC up to being used with a wide range of driver amplifier solutions. Because the AD4080 offers exceptionally low noise, and excellent levels of precision at sampling rates up to 40 MSPS with remarkably efficient power consumption, this presents signal chain choices on which application parameters to prioritize. As is often the case, there can be some competing parameters to consider. Wider bandwidth amplifiers are required to drive faster ADCs because the settling

bandwidth and signal bandwidth increase, so too does the noise bandwidth. In addition, as these speeds increase, maintaining precision in a driving amplifier becomes a greater challenge. These challenges are often met by increased power in the driver; however, Analog Devices, Inc., offers a wide choice of power efficient driver amplifiers that can be found on the [Differential Amplifiers and](https://www.analog.com/en/product-category/differential-amplifiers-and-adc-drivers.html) [ADC Drivers](https://www.analog.com/en/product-category/differential-amplifiers-and-adc-drivers.html) web page. Also, due to the Easy Drive features of the AD4080, where the settling bandwidth is relaxed considerably, products such as the [ADA4945-1](https://www.analog.com/ada4945-1) fully differential amplifier (FDA) make an excellent low power companion product. Table 12 offers some other suggested products for consideration.





<sup>1</sup> Combined quiescent current of two amplifiers.

# <span id="page-29-0"></span>**REFERENCE CIRCUITRY DESIGN**

The AD4080 requires a low noise, high precision and stability, and low temperature drift external reference of 3 V. This reference defines a differential input range for the ADC of  $\pm V_{RFFIN}$ . The reference must be within ±5 mV of +3 V. Recommended references are [LTC6655](https://www.analog.com/ltc6655), [LT6657](https://www.analog.com/lt6657), or [ADR4530](https://www.analog.com/adr4530). For best performance, however, use the LTC6655 external reference. Table 13 details the typical parameters of the previously mentioned references, comparing absolute accuracy, noise, temperature drift, load regulation, and power consumption. For more detailed specifications, refer to the data sheet of the given product.

*Table 13. Comparison of the Main Parameters of the LTC6655, LT6657, and ADR4530 References*



There is no need for the external reference capacitor because the AD4080 embeds one internally, 9.4 μF, (see Figure 46). The REFIN reference input pin is internally buffered, which substantially reduces ADC conversion transients and isolates the external reference from these transients. Therefore, no external amplifier is required to buffer the external reference. For the reference input capacitance (C  $_{REF IN}$ ) and reference output capacitance (C  $_{REF \, OUT}$ ) values, refer to the given external reference IC data sheet recommendations. As a layout recommendation, the external reference chip must be placed as close as possible to the AD4080 and its REFIN pinto minimize the series impedance of the track connecting the REFIN pin to the external reference output. It is recommended to minimize the exposure of this track to noisy signals, especially digital ones.



*Figure 46. AD4080 General External Reference Design Functional Diagram*

#### **DATA INTERFACE CLOCKING SOLUTION**

When designing the LVDS data interface (see the [LVDS Data Inter](#page-43-0)[face](#page-43-0) section), the user must ensure the clocking solution adheres to the timing specifications of the AD4080 (see [Table 2](#page-5-0)). When configured for LVDS mode data interface, the user must ensure that timing specifications stay within the maximum conversion to clock alignment time of  $\pm 535$  ps (t<sub>CCA</sub>). In addition, ensure that a low jitter conversion (CNV) clock is provided such that there is no unwanted impact to SNR performance. This jitter is signal frequency dependent; therefore, the level of jitter tolerable in a given system is dependent on the application use case. The Analog Devices Technical Article [Maximum SNR vs Clock Jitter](https://www.analog.com/en/resources/technical-articles/maximum-snr-vs-clock-jitter.html) provides further guidance on this topic.

For example, a recommended clocking solution for where the AD4080 is configured to use the LVDS data interface with a single lane enabled and using echo clock mode. In this example, a 25 MHz oscillator is selected with low phase noise and jitter. The following [MT-008](https://www.analog.com/MT-008) tutorial serves as an aid to convert between phase noise and RMS phase jitter, often quoted interchangeably in crystal oscillator product data sheets. The [ADF4350](https://www.analog.com/adf4350) wideband synthesizer with an integrated voltage-controlled oscillator (VCO) serves as versatile means of generating a 400 MHz clock system clock, while maintaining low jitter and offering flexibility and control to reconfigure this frequency depending on the application needs. This clock then feeds the [AD9508](https://www.analog.com/ad9508) clock fanout buffer with output dividers that can be configured for the desired LVDS level signaling. In the example shown in [Figure 47](#page-30-0), one output channel is set to divide by 1 to output the LVDS clock, while another output channel is configured to divide by 10 to output the AD4080 conversion clock. This 1:10 ratio of CNV:CLK frequencies ensures 20 bits of data can be read out in on the double data rate (DDR), single lane, LVDS data interface. For a dual lane configuration, such as shown in [Figure 48,](#page-30-0) this ratio is adjust to 1:5.

The example shows that echo clock mode is used and aids data alignment for the host controller (in the case a field-programmable gate array (FPGA)). In self clock mode, where DCO+ and DCO−

<span id="page-30-0"></span>are not available for alignment, the [ADC Result Latency and LVDS](#page-46-0) [Interface Alignment](#page-46-0) section describes how the INTF\_CHK\_EN bit (Address 0x15, Bit 4) can be enabled to help align the host controller to data and to mitigate against any system propagation delays.



*Figure 47. Single Lane, LVDS Data Interface Clocking Example*



*Figure 48. Dual Lane, LVDS Data Interface Clocking Example*

In cases where the SPI data interface (see the [SPI Data Interface](#page-49-0) section) is used to access conversion results from the result FIFO (see the [Result FIFO](#page-54-0) section) again, it is important that the CNV source jitter is carefully considered to achieve the required performance. In the case shown in the SPI data interface clocking example (see Figure 49) , an oscillator directly provides the conversion clock, and the data is asynchronously clocked from the FIFO by a microcontroller unit (MCU). Optionally, as shown in Figure 49, the general-purpose input and output pins can be configured to control the result FIFO operation (see the [GPIO Pins](#page-50-0) section and the [Result FIFO](#page-54-0) section).



*Figure 49. SPI Data Interface Clocking Example*

#### **POWER SOLUTION**

With such low noise and up to a 40 MHz sampling rate, it is important that careful consideration is taken for the power solution of applications to ensure that the low noise supplies provided to the AD4080 do not become a source of performance or accuracy degradation. To aid ease of use and to help reduce external required components, two internal LDO regulators are integrated within the AD4080. Further details on these regulators can be found in the [Internally Regulated Supply Configuration](#page-22-0) section. Also, note that the internal supply decoupling capacitors are included for all supply rails, whether generated internally or externally, reducing external component count, simplifying use, and offering huge benefits to PCB layout, routing, and design density.

For externally generated supply rails, excellent choice LDO regulators are the [LT3045 o](https://www.analog.com/lt3045)r [ADP150](https://www.analog.com/adp150), which both offer ultra-low noise and excellent power supply rejection. For high efficiency, step-down switching regulators, the [LT8604C](https://www.analog.com/lt8604) is a good choice; however, great care must be taken in the design of the switching regulator circuity because switching frequencies are likely to be within the application signal bandwidth, and although the AD4080 has high AC power supply rejection on its supplies, appropriate consideration must be given to the supply rails.

#### <span id="page-31-0"></span>**OVERVIEW**

The AD4080 digital interface consists of a 4-wire SPI for device configuration, four general-purpose input and output (GPIO) pins, a conversion data access interface with selectable output format (LVDS or SPI data interface), and a conversion start input (CNV+ and CNV−) that can be configures for LVDS or CMOS level signaling.

#### **Register Interface**

The AD4080 configuration registers are accessed through the SPI configuration interface (see the SPI Configuration Interface section).

# **ADC Conversion Control**

The ADC acquires a sample and initiates a conversion operation on the rising edge of the convert start signal, applied at the CNV+ and CNV− pins. There are two possible configurations for the electrical signaling at the convert start input pins: CMOS or LVDS.

CMOS is the default mode on power up and after reset. CMOS requires that the CNV− pin be tied to the digital interface ground (IOGND). In this mode, the convert signal must be a CMOS logic signal referenced to IOGND and applied at CNV+, with logic levels according to the digital inputs (CNV, GPIOx, DCS, and DCLK) parameters in [Table 1](#page-2-0).

To switch to LVDS mode, the LVDS\_CNV\_EN bit of the ADC Data Interface Configuration B register (see the [ADC Data Interface Con](#page-83-0)[figuration B Register s](#page-83-0)ection, Address 0x16) must be set to 1. In this mode, an external 100  $Ω$  termination resistor must be installed between the CNV+ and CNV− pins, as close to the AD4080 as possible. In LVDS mode, the CNV+ and CNV− pins must be driven differentially with an LVDS driver conforming to the levels specified in the LVDS I/O (EIA-644) parameters in [Table 1.](#page-2-0) Care must be taken to closely match the CNV+ and CNV− differential signal pair routing and to use controlled impedance to ensure signal integrity.

# **ADC Conversion Data Interface**

Two signaling format options are available to access conversion results:

- ► LVDS level signaling (LVDS data Interface)
- ► CMOS level signaling (SPI data interface)

The choice of interface is usually determined by the requirements and constraints of the application at hand. For example, if continuous fast data acquisition is required, then the LVDS signaling interface is typically the preferred option. If the application requires only noncontinuous bursts of data acquisitions, then either the LVDS or the SPI data interfaces can be used. The capabilities of the digital interface host can also determine which interface option is chosen.

Common to both the LVDS and SPI data interfaces are the following flexible features, which reduce the burden on the chosen digital host:

- ► Multilane data transfer: enables sustained data throughput at reduced interface clock speeds.
- ► Test pattern generation: facilitates interface integrity checks.

Additionally, for the LVDS only, there is the option to set a configurable output drive.

By default, the LVDS interface is selected on power up and after a reset. As can be seen in Figure 50, for LVDS, the data path of the ADC results is routed though the offset and gain correction block where there is the option to:

- ► Continuously read, directly, the raw ADC conversion results.
- ► Continuously read the ADC results processed by a user-selected digital filter (see the [Digital Filter](#page-62-0) section for details).
- ► Read up to 16k unfiltered results from the FIFO.
- ► Read up to 16k digitally filtered results from the FIFO.



*Figure 50. LVDS Data Interface Options*

If configured for the SPI data interface, as can be seen in Figure 51, the available data paths are as follows:

- ► Read up to 16k unfiltered results from the FIFO.
- ► Read up to 16k digitally filtered results from the FIFO.



*Figure 51. SPI Data Interface Data Path Options*

Additional features specific to the selected interface format are also available and are described in the [LVDS Data Interface](#page-43-0) section and the [SPI Data Interface](#page-49-0) section.

# **SPI CONFIGURATION INTERFACE**

All serial transactions between the system host and the AD4080 configuration registers are executed using the configuration SPI. Each serial transaction consists of at least one instruction phase during which the desired memory operation, that is, read or write,

and the starting address for the transaction are transmitted to the AD4080. The instruction phase is immediately followed by a data transaction phase during which one or more bytes of information is exchanged between the host and the AD4080. This content is framed by a continuous assertion of the interface chip select ( $\overline{\text{CS}}$ ) as illustrated in the generic timing presented in Figure 52 and Figure 53.







*Figure 53. Generic SPI Configuration Write Operation, CRC Enabled*



# **SPI Register Interface**

The configuration register interface is an SPI that enables both device configuration and system status monitoring. This interface is configured for 4-wire, full-duplex operation. Dedicated interface pins for the interface chip select  $(\overline{CS})$ , serial clock (SCLK), and serial data input (SDI) are intended for direct connection to the host controller. By default, at power-up or after a software reset, the configuration interface SDO function is enabled and assigned to the GPIO0 pin.

The configuration interface timing convention implemented in this design is consistent with SPI Mode 3, clock polarity (CPOL) = 1, clock phrase (CPHA) = 1. As such, the serial clock (SCLK) is expected to idle high and the state of the data pins, SDI and SDO, are updated on the falling (leading) edge of the clock such that these pin can be sampled on the subsequent rising (trailing) edge. See the ADI Analog Dialogue, [Introduction to SPI Interface](https://www.analog.com/en/resources/analog-dialogue/articles/introduction-to-spi-interface.html) article for more details regarding the SPI and SPI modes.

The memory access controller associated with this interface supports a number of user-programmable options accessible through the interface configuration memory space (Address 0x00 to Address 0x11). The available options for the AD4080 are listed and described in Table 14.





#### <span id="page-33-0"></span>*Table 14. Configuration Memory Controller Options Summary (Continued)*

#### **Instruction Phase**

An instruction phase immediately follows the assertion of the  $\overline{\text{CS}}$ pin (Logic 0) and is terminated by transmission of a complete instruction packet or deassertion of CS. The instruction packet starts with a single command bit indicating the operation type (Logic 1 for read, and Logic 0 for write), which is then followed by the start address for the operation. By default, the address is 15-bit long, but the data interface has an optional short instruction mode, in which, it is reduced to 7 bits. The short instruction mode is enabled by setting the SHORT\_INSTRUCTION bit = 1 in the Interface Configuration B register (see the [Interface Configuration B Register](#page-74-0) section, Address 0x01).

#### **Data Phase**

Each instruction phase is immediately followed by an associated data phase, during which data is either shifted out of the serial data output (SDO) on the falling edge of SCLK (read access) or is shifted into the device configuration memory through SDI on the rising edge of SCLK (write access). The minimum size of the data payload is defined as a single byte; however, it can include multiple bytes depending on the depth of the register addressed and the interface configuration settings for the SINGLE\_INST and STRICT\_REGISTER\_ACCESS bits (Register 0x01, Bit 7, and Register 0x10, Bit 5, respectively.

#### **Write Access**

When  $\overline{CS}$  is forced low, a new serial instruction phase begins. The first bit sent in the instruction phase is the command bit, and when it is forced low (Logic 0) this indicates a write operation. The command bit is followed by an address that, for the write operation, indicates where the information received in the subsequent data phase will be stored. As previously described in the Instruction Phase section, the address has a default length of 15 bits, but the address can be optionally shortened to 7 bits.

Following the instruction phase, an integer number of bytes containing the data payload for one or more registers in the configuration memory are transmitted to the AD4080. The size of the payload in this data phase is bounded by the selected SINGLE\_INST and STRICT\_REGISTER\_ACCESS interface options as described in the [Strict Access Selection and Multibyte Registers](#page-35-0) section. Each data byte is loaded into the addressed register as it is received, assuming the interface CRC is disabled. If the CRC is enabled, however, the addressed data register is only loaded if the internally computed checksum matches the CRC value received from the host. In the event that the computed CRC and received checksum

from the host for a given entity are inconsistent, the register update terminates and all subsequent data in the given frame is treated as invalid as well. The checksum computation for the interface CRC function is described in detail in the [Configuration Cyclical](#page-38-0) [Redundancy Check \(CRC\)](#page-38-0) section.

Note that, during the data phase of a write operation, the SDO output is driven to Logic 0 when the product is not reporting the latest CRC checksum to ensure a valid data state is presented to the host controllers SDI pin.

#### **Read Access**

The SPI enables read access to the configuration registers to validate previous configuration writes, read the device identification, or verify the interface status.

When  $\overline{CS}$  is forced low, a new serial instruction phase begins. The first bit sent in the instruction phase is the command bit, and when it is forced high (Logic 1) this indicates a read operation. The command bit is followed by an address that, for the read operation, indicates the start address for the register space to be accessed. As previously described in the Instruction Phase section, the address has a default length of 15 bits, but the address can be optionally shortened to 7 bits.

During the subsequent data phase, content from the addressed register space is shifted out, MSB first, on the SDO line on the falling edge of SCLK. The number of bytes transmitted in any one data frame is determined by the interface configuration setting selections for the SHORT\_INSTRUCTION and STRICT\_REG-ISTER\_ACCESS options as demonstrated in the examples shown in the Instruction Mode Selection section and the [Strict Access](#page-35-0) [Selection and Multibyte Registers](#page-35-0) section.

#### **Instruction Mode Selection**

The configuration interface memory controller defaults to streaming mode upon power up (SINGLE  $INST = 0$ ). In streaming mode, multiple, contiguous registers are accessed in a single SPI frame, starting at the address specified in the instruction phase. In streaming mode, only one instruction phase is permitted per SPI frame, requiring a new SPI frame be initiated for changing access commands or otherwise access a noncontiguous address in the register space. For each byte transferred during the subsequent data phase, the internal address counter is automatically updated according to the setting of the ADDR ASCENSION bit in the Interface Configuration A register (see the [Interface Configuration A Register](#page-73-0) section), in the way specified by [Table 15.](#page-34-0)

#### <span id="page-34-0"></span>*Table 15. Address Ascension Selection*



Figure 54 illustrates the generic SPI frame formatting for a serial transaction using the default interface configuration. In this example, a portion of the configuration register space consisting of a byte-wide register and a multibyte register is accessed. The address for the byte-wide register resides in the most significant address (ADDRESS) and the most significant byte of the multibyte register resides in the least significant address of the register segment. By default, the ADDR\_ASCENSION property is set to descending, indicating that the address for the most significant register is passed to the host controller during the instruction phase. Depending on the selected operation, the instruction word

is followed by either a payload consisting of data for the byte-wide register (DATA), least significant (LSBYTE), and most significant bytes (MSBYTE) of the multibyte register, or, in the case of a read access, padding bits. As a convention, it is recommended to pass Logic 1 to SDI during a read access to avoid accidentally addressing address zero for write access.

In single instruction mode (SINGLE\_INST = 1), the memory access controller requires an instruction phase to transmit for each register accessed in a given SPI frame as illustrated in Figure 55. This mode is useful when access to nonadjacent sections of the register space is required in a given SPI frame. Note that, the same access flexibility can be achieved in stream mode by initiating a new SPI frame for each unique register access.

The single instruction mode is selected by setting SINGLE\_INST = 1 in the Interface Configuration B register (see the [Interface](#page-74-0) [Configuration B Register](#page-74-0) section, Address 0x01).



*Figure 54. Interface Access Example, Default Interface Configuration, Streaming Mode (ADDR\_ASCENSION = 0)*



*Figure 55. Interface Access Example, Single Instruction Mode (SINGLE\_INST = 1), All Other Interface Options Default*

#### <span id="page-35-0"></span>**Address Ascension Selection**

The address ascension selection (ADDR\_ASCENSION) bit, as described in previous sections, determines how the internal interface address pointer is updated for each byte of data transmitted to the AD4080 in streaming mode (SINGLE INST = 0). If using single instruction mode (SINGLE  $INST = 1$ ), each register is directly addressed through its own instruction phase as illustrated in [Figure](#page-34-0) [55](#page-34-0), and thus, the address pointer is not updated. Regardless of the setting for SINGLE\_INST, the ADDR\_ASCENSION bit directly impacts the formatting of the SPI frame in terms of selection of the instruction phase starting address and byte order of the data phase payload. This impact is described in greater detail in the Strict Access Selection and Multibyte Registers section as much of the data formatting is dependent on this interface configuration selection. The ADDR ASCENSION selection bit is located in the Interface Configuration A register (see the [Interface Configuration A](#page-73-0) [Register](#page-73-0) section, Address 0x00).

As summarized in [Table 15,](#page-34-0) the ADDR ASCENSION bit is cleared by default, resulting in the address pointer decrementing by one for each data byte transmitted. In this decrement configuration (ADDR  $ASCENSION = 0$ ), the address pointer decrements from the starting address indicated in the instruction phase by one for each data phase byte received until the counter reaches Address 0x0000. If additional bytes are received, the pointer automatically rolls over to the maximum address value, 0x7FFF; the rollover behavior is fixed, and therefore, independent of the SHORT\_IN-STRUCTION value or the physical address space occupied by the user configurable registers. It is important to understand this behavior to avoid generating interface errors associated with attempting to access one or more invalid register addresses. Limit register access to the register address space associated with the device configuration as described in the [Configuration Registers](#page-71-0) section.

Alternatively, the ADDR\_ASCENSION bit can be set (ADDR\_AS-CENSION = 1), resulting in the address pointer incrementing by one, starting at the address identified in the instruction word, for each data phase byte received at the AD4080 in a given SPI frame. In a manner similar to the descending case, the address counter continues to increment for each data byte received until the maximum address value, 0x7FFFF, is reached, after which the pointer rolls over to 0x0000.

#### **Strict Access Selection and Multibyte Registers**

Several locations in the AD4080 configuration memory have been assigned as multibyte registers to support the storage requirements. For example, the offset correct register (see the [Offset](#page-90-0) [Correction Register](#page-90-0) section, Address 0x25) and gain correction register (see the [Gain Correction Register](#page-91-0) section, Address 0x27) are multibyte registers because the resolution of the correction coefficients they contain exceeds a single byte. For a complete listing of multibyte registers, refer to the [Configuration Registers](#page-71-0)

section. The length of each register, in bytes, is captured in [Table](#page-71-0) [31](#page-71-0) in addition to other characteristic information.

The function of the STRICT\_REGISTER\_ACCESS bit is to indicate to the interface controller that all bytes of a multibyte register must be accessed in the current frame for valid communication to have occurred. In the event a multibyte register is only partially accessed, an interface fault is generated in the Interface Status A register (see the [Interface Status A Register](#page-80-0) section, Address 0x11), and the partial content update is discarded. The intent of this restriction is to ensure that corresponding configuration quantities are updated in a manner that produces the desired device operation. The access restriction function is enabled by default (STRICT\_REGIS-TER  $ACCESS = 1$ ) and can be disabled by clearing the access bit (STRICT\_REGISTER\_ACCESS = 0) in the Interface Configuration C register (see the [Interface Configuration C Register](#page-79-0) section, Address 0x10). With register access restriction disabled, each byte of the configuration memory can be independently addressed; however, it is then incumbent on the software to correctly configure any multibyte registers in the device memory to achieve the desired behavior.

The decision to enable or disable the register access restriction has implications with regards to the correct construction of the SPI frames containing one or more multibyte register accesses. When STRICT\_REGISTER\_ACCESS is disabled, each byte of a multibyte register is treated as a singular element. Furthermore, the interface does not indicate a fault if all bytes of the register are not programmed, or if the bytes are programmed in a random order, and therefore, it is incumbent on the host to ensure that the content of those registers are updated in a manner that produces the desired function in the device.

When STRICT\_REGISTER\_ACCESS is enabled, specific access rules are enforced to ensure consistency between the data and the expected behavior of the device. To understand how these rules apply to multibyte registers in the configuration memory, it is important to understand how the memory is organized. By convention, multibyte registers are arranged in the configuration memory such that the most significant byte of the register is stored in the most significant address of the assigned register space as illustrated in [Figure 56.](#page-36-0) As a result, the byte order of the register content transmitted in the data phase is dependent on the ADDR\_ASCENSION selection.


*Figure 56. Generic Byte Wide Memory, Multibyte Register Example*

As indicated in Figure 57, the address counter, by default, automatically decrements (ADDR\_ASCENSION = 0) such that the most significant byte of the multibyte register is accessed first, followed

by the remaining byte(s) in that register in ascending order. Conversely, if ADDR\_ASCENSION = 1, the least significant byte of the multibyte register is accessed first followed by most significant byte.

As an extension of this concept, when STRICT\_REGISTER\_AC-CESS = 1, any SPI frame that accesses a multibyte register as the first entity in the data transfer must correctly set the starting address in the instruction word to correspond to the ADDR\_AS-CENSION selection. In the case that the address counter automatically decrements (ADDR  $ASCENSION = 0$ ), the starting address is assigned to the register address for the least significant byte of that multibyte register, and conversely, if configured to increment automatically, the starting address must be set to the register address for the most significant byte. As a result of the change to ADDR\_ASCENSION from automatic address decrement (0) to automatic increment (1), [Figure 54](#page-34-0) and [Figure 55](#page-34-0) will change as illustrated in Figure 57 and Figure 58 to accommodate the changes in data phase byte order and instruction phase multibyte register start address.



*Figure 57. Single Instruction Format, ADDR\_ASCENSION = 0 (Descend), STRICT\_REGISTER\_ACCESS = 1 (Enabled)*



*Figure 58. Single Instruction Format, ADDR\_ASCENSION = 1 (Increment), STRICT\_REGISTER\_ACCESS = 1 (Enabled)*

#### **Status Data Transmission**

The Interface Status A register (see the [Interface Status A Reg](#page-80-0)[ister](#page-80-0) section, Address 0x11) and device status register (see the [Device Status Register](#page-81-0) section, Address 0x14) contain status data pertaining to the communications interface and the device itself, respectively. This data enables troubleshooting of device configuration during development and also provides continuous coverage of potential communication issues between the host and the interface once deployed. The SPI controller can access the data through regular register read operations. However, the AD4080 can be configured to autonomously transmit status data through the SDO line every time while the SPI controller is sending the SPI instruction

phase data over the SDI. This feature is controlled through the SEND STATUS bit in the Interface Configuration C register (see the [Interface Configuration C Register](#page-79-0) section, Address 0x10), and it is disabled by default. To enable this bit, set SEND\_STATUS = 1. The status data that is sent is taken from the Interface Status A register and from the device status register, but the content is different depending on the setting of the SHORT\_INSTRUCTION bit in the Interface Configuration B register (see the [Interface Configuration](#page-74-0) [B Register](#page-74-0) section. (Note that the length of the instruction phase also depends on this setting). See Table 16 and [Table 17](#page-38-0) for a description of the status data sent in each case, where the status data is sent MSB first.





#### <span id="page-38-0"></span>*Table 16. Device Status Data Sent Through the SDO in Long Instruction Mode (SHORT\_INSTRUCTION = 0) (Continued)*



#### *Table 17. Device Status Data Sent Through the SDO in Short Instruction Mode (SHORT\_INSTRUCTION = 1)*



#### **Configuration Cyclical Redundancy Check (CRC)**

The AD4080 includes optional configuration error detection based on an 8-bit cyclical redundancy check algorithm. When enabled, an 8-bit checksum is inserted into the serial data output stream (SDO) during the data phase after each complete register transaction. Depending on the register access type,that is, read or write, the host is expected to conditionally provide a corresponding checksum to the SDI immediately following each register access. The interface controller uses the host supplied checksum to determine if a CRC error has occurred.

A mismatch in the checksum values computed by the host and the AD4080 interface results in setting the CRC\_ERR flag (CRC\_ERR = 1) in the Interface Status A register (see the [Interface Status](#page-80-0) [A Register](#page-80-0) section, Address 0x11). During a write access, a CRC error invalidates the most recent register data as well as any subsequent register data writes if in streaming mode (SINGLE\_INST = 0), which prevents loading any potentially corrupted data into the configuration memory. In response to a CRC event, the host

controller is required to initiate a new SPI frame to retry configuration of the effected memory locations. In the event the CRC\_ERR is detected during a data read, the host controller must discard the received data and retry the data read in a new SPI frame. Clear the CRC\_ERR flag before any attempt to initiate a repeated read or write to the configuration memory to allow detection of any subsequent errors. The error flag is cleared by writing code 0x08 to the Interface Status A register to set the CRC\_ERR bit to a Logic 1. It is recommended that an immediate read of the Interface Status A register follows any attempt to clear the fault to validate the attempt was successful.

The configuration CRC function is disabled by default and can be enabled through two complementary bit fields, CRC\_ENABLE and CRC\_ENABLEB, in the Interface Configuration C register (see the [Interface Configuration C Register](#page-79-0) section, Address 0x10). To enable the CRC function, set the CRC\_ENABLE bits to 1 and the CRC\_ENABLEB bits to 10. Each of the complementary CRC bit fields is 2-bit wide, and any combination other than that specified results in the function remaining disabled. It is important to note that once the CRC function is enabled, a valid checksum from

the host controller is required for all subsequent serial transactions according to the conditions described in Table 18. If used, enable and validate the CRC function before writing to any of the device configuration registers. To validate the CRC function is enabled, follow the CRC configuration write with a SPI frame consisting of a read of both the Interface Configuration C register and the Interface Status A register using a valid checksum for the read transaction. If enabled, the register contents for the CRC\_ENABLE and CRC\_EN-ABLEB bits must be 1 and 10, respectively, and the CRC\_ERR bit in the Interface Status A register remains cleared (Logic 0). Once confirmed, proceed with programming the remaining configuration registers.

*Table 18. Host Controller (SDI) Conditional Checksum Requirement Summary*



The following CRC-8 polynomial is implemented in the AD4080 to compute the checksum for each register transaction:

#### $x^8 + x^2 + x + 1$

Each serial transaction is processed through this polynomial to generate the checksum on a per register basis. The data and seed values used for each checksum calculation are a function of the access command (read/write); ADDR\_ASCENSION, STRICT\_REG-ISTER\_ACCESS, and SINGLE\_INST settings; and the location of the register data in the data stream as summarized in Table 19.

All register write access operations, regardless of SINGLE\_INST setting, require a valid CRC checksum to be sent from the host following the data payload for each register. For multibyte registers, if STRICT\_REGISTER\_ACCESS = 1, a valid CRC is appended to the data stream after all bytes of the addressed register are sent. If STRICT\_REGISTER\_ACCESS is cleared (0), each byte transmitted must be followed by a valid checksum using the computation rules that are described as follows.

For read access, the computation and transmission of a valid checksum from the host is required to validate the command and starting address only. In streaming mode (SINGLE INST = 0), a CRC checksum is sent from the host controller after the first register data payload only. Fill all subsequent register accesses in streaming mode with padding data. The AD4080 continues to produce valid checksum values after each register read to allow validation in the host using the preceding data. As a new instruction phase is required for each register accessed in single instruction mode, a valid host CRC checksum is required for each register accessed.

In single instruction mode (SINGLE\_INST = 1), the polynomial is computed for each register using the default seed value of 0xA5, the instruction phase data, and depending on the access command, the desired register or padding data. In streaming mode  $(NI)$  (SINGLE INST = 0), the checksum computation for the first register in the data stream is computed as if single instruction mode were selected. Each subsequent register access checksum computation is seeded with the starting address for the current register and the corresponding data. Note that the starting address for multibyte registers changes with the ADDR\_ASCENSION selection, assuming the register access restriction is enabled (STRICT\_REGISTER\_AC-CESS = 1). As previously described, the memory convention dictates that if ADDR\_ASCENSION is set to 0, the address for the least significant byte of the multibyte register serves as the starting address. Conversely, if the ADDR\_ASCENSION bit is set to 1, the address of the most significant byte of the multibyte register is used.







*Figure 59. Streaming Mode Configuration with CRC Enabled, ADDR\_ASCENSION = 1*







*Figure 61. Streaming Mode Configuration with CRC Enabled, STRICT\_REGISTER\_ACCESS = 0 (Disabled) , ADDR\_ASCENSION = 0*

 $^{96}$ 

# **Configuration SPI Frame**



*Figure 62. Short Instruction Mode, Data Status Enabled, CRC not Enabled*



*Figure 63. Short Instruction Mode, Data Status Enabled, CRC Enabled*



*Figure 64. Long Instruction Mode, Data Status Enabled, CRC not Enabled*



*Figure 65. Long Instruction Mode, Data Status Enabled, CRC Enabled*

# **Configuration SPI Timing**

#### **Write Data Frame**



*Figure 66. Configuration SPI Timing, Data Write Frame, 16-Bit Instruction Mode (Default)*



*Figure 67. Configuration SPI Timing, Data Write Frame, 8-Bit Instruction Mode, Single 8-Bit Register*



*Figure 68. Configuration SPI Timing, Data Write Frame, 8-Bit Instruction Mode, Streaming Mode, Multibyte Register*

# **Read Data Frame**



*Figure 69. Configuration SPI Timing, Data Read Frame, 16-Bit Instruction Mode (Default)*



*Figure 70. Configuration SPI Timing, Data Read Frame, 8-Bit Instruction Mode*



*Figure 71. Configuration SPI Timing, Data Read Frame, 8-Bit Instruction Mode, Steaming Mode, Multibyte Register*



*Figure 72. Configuration SPI Timing, Data Read Frame, Continuous SCLK*

#### **LVDS DATA INTERFACE**

#### **LVDS Data Interface Configuration**

The LVDS interface consists of up to five pairs of differential signals. The data clock input pair (CLK+ and CLK−), echoed data clock output pair (DCO+ and DCO−), two data output lanes (DA+ and DA− , DB+ and DB− ), and optionally, the conversion clock can be configured as either an LVDS pair (CNV+ and CNV−) or as a CMOS using CNV+, where for this case, CNV− is connected to GND. This user selection is configured using the LVDS\_CNV\_EN bit in the [ADC](#page-83-0) Data Interface Configuration B register (see the ADC [Data Interface Configuration B Register](#page-83-0) section, Address 0x16). The data lanes use a DDR scheme, and each scheme can support a throughput of up to 800 (Mbps). By default, LVDS is selected as the primary data interface for accessing conversion results.

To achieve maximum throughput, it is necessary that while a conversion is performed the result of the previous conversion is read. For this reason, it is critical that both the rising and falling edges of CNV+ and CNV− are closely time aligned to the rising edge of CLK+ and CLK−. To avoid introducing noise into the conversion result, the CLK+ and CLK− edge placement must be aligned to within  $\pm 535$  ps (t<sub>CCA</sub>) of the interface clock (CLK $\pm$ ), as specified in [Table 2](#page-5-0).

The data interface is highly configurable allowing the customization of the output stream to meet a wide range of applications. Configuration options include the number of active lanes (1, 2), self clocked and echo clock modes, interface test functions, and data encoding. LVDS interface mode is used in applications where continuous conversion at rates exceeding 1 MHz is required.

Transmission of the result data occurs MSB first and is output after the amount of time specified in detail in the [ADC Result Latency](#page-46-0) [and LVDS Interface Alignment](#page-46-0) section.

#### **LVDS Active Data Lane Count**

The LVDS interface can be configured to output the result data on either one or two data lanes, which is controlled by the SPI\_LVDS\_LANES bit in the ADC Data Interface Configuration A register (see the [ADC Data Interface Configuration A Register](#page-82-0) section, Address 0x15). By default, this bit is set to 0 (one lane active), and setting SPI\_LVDS\_LANES = 1 uses two data lanes. Note that this bit is also used to configure the number of active data lanes for the SPI.

In single lane operation, Data Lane DA+ and Data Lane DA− is enabled as the primary data output, and the conversion result is shifted out serially, MSB first, using 10 interface clocks applied to CLK+ and CLK− inputs per conversion. The result data is shifted out of the device on each edge of the echo clock outputs, DCO+ and DCO−. The result MSB (D19) and all odd numbered data bits are output on the falling edge of the interface clock. Conversely, the even numbered data bits are output on the rising edge of the interface clock.

In dual lane configuration, the result data is shifted out in parallel, 2 bits per clock edge, MSBs first. As a result, only five interface clocks are required per conversion. As the data access period is equivalent to the conversion period, the interface clock frequency is reduced by a factor of two relative to the single lane case. As a consequence of the increased interface clock period, see the [ADC](#page-46-0) [Result Latency and LVDS Interface Alignment](#page-46-0) section for the timing and latency implications on both the single lane and dual lane count configurations.

#### <span id="page-44-0"></span>**Echo Clock Mode**

In LVDS data interface mode, the DCO+ and DCO− pin pair is an echo clock output that provides a buffered and delayed version of CLK+ and CLK− pin pair, facilitating data clocking to the host controller data clocking. This feature is controlled by the LVDS\_SELF\_CLK\_MODE bit in the ADC Data Interface Configuration B register (see the [ADC Data Interface Configuration B Regis](#page-83-0)[ter s](#page-83-0)ection, Address 0x16). By default, echo clock mode is active (LVDS\_SELF\_CLK\_MODE = 0). Setting LVDS\_SELF\_CLK\_MODE = 1 disables the DCO+ and DCO− output driver, putting the device in self clock mode (see the [Self Clock Mode](#page-45-0) section) .

When echo clock mode is active, the interface requires a minimum of three LVDS pairs (CLK+ and CLK−, DCO+ and DCO−, and DA+ and DA−) to be connected between the host controller and the AD4080. A maximum of five LVDS pairs are required if the CNV+ and CNV− pin pair is configured as an LVDS input and the DB+ and DB− data lane is enabled. The conversion clock (CNV+ and CNV−) and data clock (CLK+ and CLK−) can be shared amongst multiple AD4080 devices as long as care is taken to fanout the clock network, such that the edge placement requirement is satisfied.

In echo clock mode, data from enabled lanes is clocked out in sync to both rising and falling edges of DCO+ and DCO− in a DDR scheme. Figure 73 and Figure 74 illustrate the relevant LVDS interface timing with respect to the DCO+ and DCO− echo clock for single lane and dual lane configurations, respectively. Calculation of  $t_{MSR,RFAD}$  is described in the [ADC Result Latency and LVDS](#page-46-0) [Interface Alignment](#page-46-0) section.

Consider matching the data clock (DCO+ and DCO−) and data lane (DA+ and DA−, DB+ and DB−) lane routing from the ADC to the host processor for the physical layout to minimize timing skew, which may affect data recovery in the host. For additional routing suggestions, see the [Layout Guidelines](#page-70-0) section.



*Figure 73. Continuous Conversion Timing, LVDS Data Interface, Single Data Lane, Echo Clock Mode*



*Figure 74. Continuous Conversion Timing, LVDS Data Interface, Dual DataLane, Echo Clock Mode*

# <span id="page-45-0"></span>**Self Clock Mode**

In LVDS data interface mode, it is possible to disable the DCO+ and DCO− echo clock output (see the [Echo Clock Mode](#page-44-0) section) by setting LVDS\_SELF\_CLK\_MODE = 1 in the ADC Data Interface Configuration B register (see the [ADC Data Interface Configuration](#page-83-0) [B Register s](#page-83-0)ection, Address 0x16). This setting puts the device in self clock mode disabling the DCO+ and DCO− output driver, with the benefit of saving interface power as well as reducing the

number of LVDS pairs required to interface with the host controller. In this mode, the DCO+ and DCO− pins can be left disconnected; therefore, in single-lane configurations, a minimum of two LVDS pairs (CLK+ and CLK−, DA+ and DA−) are required to connect to each AD4080 instance. The interface connectivity can further be simplified by sharing the interface clock (CLK+ and CLK−) between multiple AD4080 instances.



*Figure 75. Continuous Conversion Timing, LVDS Data Interface, Single Data Lane, Self Clock Mode*



*Figure 76. Continuous Conversion Timing, LVDS Data Interface, Dual Data Lane, Self Clock Mode*

# <span id="page-46-0"></span>**LVDS Manchester Encoding Mode**

This mode is accessed via the ADC\_DATA\_INTF\_CONFIG\_B register (Address 0x16), which produces Manchester encoding of the result data in compliance with IEEE 802.3. This mode can be used in isolated data applications where the converter supplies can be floated and the data outputs capacitively coupled to the host controller. By ensuring that the mean output of each data lane is 0, the receiver side common-mode voltage is not disturbed by the result pattern.

Manchester encoding is available in dual lane LVDS mode only so that the maximum data throughput is achievable with the maximum 400 MHz LVDS clock rate.

Figure 77 shows an example how this isolation can be implemented. Note that the LVDS 100  $\Omega$  termination resistor prior to the isolation capacitors is required.



*Figure 77. Isolated LVDS*

## **ADC Result Latency and LVDS Interface Alignment**

WhenAD4080 is configured for LVDS interface mode, each conversion result is placed into the LVDS interface output shift register(s). The LVDS\_CNV\_CLK\_CNT bits in the ADC Data Interface Configuration B register (see the [ADC Data Interface Configuration B](#page-83-0) [Register s](#page-83-0)ection, Address 0x16) is used to configure the point in time when the conversion result data is loaded into the LVDS interface output shift register(s). The total time from the rising edge of a convert pulse to when the MSB of that conversion request is internally available to transfer to the output register is defined as  $(t_{\rm CYC} + t_{\rm MSB})$ , both specified in [Table 2](#page-5-0). Because the transfer of this result data is under the control of the LVDS of CLK+ and CLK−, there is an additional (1.5  $\times$  t<sub>CLK</sub>) that must be allowed to guarantee a fully completed result is transferred to the interface for read back. The user must calculate the correct required LVDS\_CNV\_CLK\_CNT value and configure the ADC Data Interface Configuration B register (see the [ADC Data Interface](#page-83-0) [Configuration B Register](#page-83-0) section) according to the conversion rate and  $t_{\text{Cl K}}$  used.

For minimum latency, the correct LVDS\_CNV\_CLK\_CNT value to use for a particular conversion rate is calculated as  $(t_{\text{MSR}}/t_{\text{CI K}} +$ 1.5). This number is rounded down to the nearest integer value.

The maximum  $t_{\text{MSB}}$  time is specified as 22.4ns with gain error correction enabled (see the [Gain Error Correction](https://ccms.web.analog.com/oxygen-webapp/app/Keyref%20tdi1697028251825) section). For a 40 MSPS conversion rate in single lane LVDS with a 400 MHz LVDS clock, this is calculated as 22.4ns/2.5 ns + 1.5, yielding a setting of 10 for the LVDS\_CNV\_CLK\_CNT. Conversion latency is then determined as time, aligned to the falling edge of the CLK signal, described as  $t_{\text{MSB}}$  READ or latency in the timing diagram, which can be calculated as (LVDS\_CNV\_CLK\_CNT + 0.5)  $\times$  t<sub>CLK</sub>. For the given example, the single lane latency is calculated as (10+  $(0.5) \times 2.5$  ns + t<sub>CYC</sub> = 51.25 ns latency.

Taking a dual lane example, the same formula is used, again taking a 40 MSPS example, again with gain error correction enabled, the LVDS clock runs at 200 MHz and yields ( 22.4ns/5 ns) + 1.5, resulting in an LVDS\_CNV\_CLK\_CNT of 5, and a total result latency of  $(5 + 0.5) \times 5$  ns + t<sub>CYC</sub> = 52.50 ns latency.

With the gain error correction disabled (see the [Gain Error Correc](https://ccms.web.analog.com/oxygen-webapp/app/Keyref%20tdi1697028251825)[tion](https://ccms.web.analog.com/oxygen-webapp/app/Keyref%20tdi1697028251825) section), the maximum t<sub>MSB</sub> time is specified as 18 ns. For a 40 MSPS conversion rate in single lane LVDS with a 400 MHz LVDS clock, this is calculated as 18 ns/2.5 ns + 1.5, yielding a setting of 8 for the LVDS\_CNV\_CLK\_CNT. Conversion latency is then determined as time, aligned to the falling edge of the CLK signal, described as  $t_{\text{MSB}}$  READ or latency in the timing diagram, which can be calculated as (LVDS CNV CLK CNT + 0.5)  $\times$  t<sub>CLK</sub>. For the given example, the single lane latency is calculated as (8 +  $(0.5) \times 2.5 + t_{CYC} = 46.25$  ns latency.

Both of these examples are calculated to achieve the minimum latency, and it is possible to use a higher LVDS CNV CLK CNT value, whereby latency is increased by  $t_{\text{Cl K}}$  for each +1 unit increase in the LVDS\_CNV\_CLK\_CNT value.

[Figure 78](#page-47-0) and [Figure 79](#page-47-0) serve as aids to describe the placement of the ADC result data onto the LVDS interface controlled by the LVDS CNV CLK CNT. [Figure 78](#page-47-0) shows that a new result is internally completed after ( $t_{\text{CYC}}$  +  $t_{\text{MSB}}$ ), and this result is now available to the interface, signified here also by a notional  $t_{\text{MSB-AVALABLE}}$ (introduced only for the purposes of the [Figure 78](#page-47-0) explanation). As this example represents a 40 MSPS conversion rate, [Figure 78](#page-47-0) shows that the LVDS CNV CLK CNT setting of 10 is the earliest the conversion result can be loaded to the LVDS interface. One additional full  $t_{CLK}$  cycle is required (a complete cycle being  $CLK+$ falling edge to next CLK+ falling edge) is required to move the MSB to the output. This cycle is highlighted within [Figure 78](#page-47-0) also with a notional t<sub>MSB, RFAD</sub> indicator for illustrative purposes only.

<span id="page-47-0"></span>

*Figure 78. Single Lane LVDS, Echo Clock Mode, LVDS\_CNV\_CLK\_CNT Position Example*



*Figure 79. Dual Lane LVDS, Echo Clock Mode, LVDS\_CNV\_CLK\_CNT Position Example*

#### *Table 20. Valid LVDS\_CNV\_CLK\_CNT Settings*



As a overview guide, [Table 21](#page-48-0) indicates the minimum required LVDS\_CNV\_CLK\_CNT settings for various conversion rates.

The maximum  $t_{MSB}$  of 22.4ns, that is with the gain error correction enabled (see the [Gain Error Correction](https://ccms.web.analog.com/oxygen-webapp/app/Keyref%20tdi1697028251825) section), is used for all calculations in [Table 21](#page-48-0). On power-up, the value of the gain error correction is 0x200, disabling the correction and allowing for a lower latency result. In this case,  $t_{\text{MSB}}$  is 18 ns and a latency of 46.25 ns can be achieved.

Using this example, the same formula is used, again taking a single lane 40 MSPS example, the LVDS clock runs at 400 MHz and yields (18 ns/2.5 ns) + 1.5, resulting in an LVDS\_CNV\_CLK\_CNT of 8 and a total result latency of  $(8 + 0.5) \times 2.5$  ns + t<sub>CYC</sub> = 46.25 ns latency.

To aid alignment of this valid result data position with the digital host of the user, the ADC Data Interface Configuration A register (see the [ADC Data Interface Configuration A Register](#page-82-0) section, Address 0x15) contains access to the interface check feature enabled by setting the INTF\_CHK\_EN bit. When this bit is set, the ADC results are no longer output on the interface, and the output is replaced with a fixed pattern 20b1010 1100 0101 1101 0110 (0xA C5D6).

<span id="page-48-0"></span>This feature allows the user to align and test the data interface to their digital host. When the INTF\_CHK\_EN bit is unset, the normal conversion results are output to the LVDS interface immediately. This method is useful for alignment, particularly for self clock mode cases where unknown PCB propagation delays may be present

between the AD4080 and its digital host controller. Note that this feature was specifically designed to help output LVDS data with the LVDS clock of the digital host by using static data, and the feature does not indicate if the LVDS\_CNV\_CLK\_CNT setting is used.





#### **LVDS Data Transfer Latency**

Where the user is concerned in knowing the overall latency from when an individual ADC conversion is initiated to the time when the LSB has reached the host controller, it is important to consider the data transfer latency. The total latency observed is the sum of the ADC latency and the data transfer latency, in this case, the LVDS\_CNV\_CLK\_CNT is set to achieve minimum ADC latency. Additional clock cycles more than the minimum required incur additional LVDS clock cycles of latency to the overall latency, as is shown in Figure 80.

The data transfer latency on the LVDS interface depends on the following parameters:

► LVDS clock period,  $t_{\text{CLK}}$ 

 $\triangleright$  Number of active LVDS lanes, N<sub>LANES</sub>

 $\triangleright$  Number of bits to be read, N<sub>BITS</sub>

Calculate the latency as follows:

Data Transfer Latency  $= \frac{N_{BITS}}{N_{LANES}} \times t_{CLK}$ 

For applications that require extremely low latencies, note that as the data is transferred MSB to LSB in both single and dual lane modes, and that there is no requirement to fully read a result from the interface, the data transfer latency can be reduced for lower resolution results (that is,  $N<sub>BITS</sub>$  can be chosen to be smaller than the maximum 20 bits available).





# **LVDS Output Differential Drive**

The AD4080 supports selection of the LVDS output differential voltage from one of three predetermined differential amplitudes of  $\pm$ 185 mV p-p,  $\pm$ 240 mV p-p, and  $\pm$ 325 mV p-p assuming a termination resistance of 100 Ω across the differential pair. The output common-mode voltage of the LVDS drive is adjusted for each selection automatically to ensure that the peak output voltage remains within the IOVDD rail. The current default selection sets the differential amplitude at ±240 mV p-p. The output differential voltage can be modified by writing to the LVDS\_VOD bits of the ADC Data Interface Configuration C register (see the [ADC Data](#page-83-0) [Interface Configuration C Register](#page-83-0) section, Address 0x17).

#### **Data Interface Test Functions**

Regardless of the selected output configuration, the AD4080 is equipped with self test functions that enable verification of the integrity of the data interface physical layer, including device pads, PCB interconnect, and the host interface connections. An interface check function is available setting a fixed, 20-bit data pattern mode to output. Selection of this test function is made by writing to the INTF\_CHK\_EN bit in the Data Interface Configuration A register (see the [ADC Data Interface Configuration A Register](#page-82-0) section, Address 0x15).

By enabling the built-in test function, access to conversion results is suspended; therefore, only use this function at either power-up or during an idle period when conversion results are not required for normal system function.

Refer to the [ADC Result Latency and LVDS Interface Alignment](#page-46-0) section for further information.

#### **SPI DATA INTERFACE**

#### **SPI Data Interface Configuration**

For applications that do not require the interface bandwidth of the LVDS interface, such as when using asynchronous capture into the result FIFO, the data interface can be reconfigured into a single or quad lane, SPI data interface. In this configuration, the AD4080 outputs data on either one or four CMOS data lanes simultaneously at serial clock rates up to 50 MHz. The result data is shifted out serially on the falling edge of the interface clock (DCLK). In SPI configuration, the AD4080 results can be read at interface rates up to 200 MHz when using four SPI lanes.

To select the SPI configuration, program the DATA\_INTF\_MODE bit of the Data Interface Configuration A register (see the [ADC](#page-82-0) [Data Interface Configuration A Register](#page-82-0) section, Address 0x15) with Binary Sequence 1'b1. Once configured for SPI mode, the AD4080 LVDS drivers are automatically disabled, including the echo clock output (DCO+ and DCO−), preventing contention between LVDS and CMOS functions. As a result, the LVDS\_SELF\_CLK\_MODE and LVDS\_VOD settings no longer effect the operation of the data

interface and can be left at their power-on defaults or another convenient value. Because the driver is disabled, the DCO+ and DCO− output pins can, therefore, be left disconnected in the hardware design as these pins are unused.

As detailed in Table 22, the following LVDS pins are reconfigured as CMOS input or outputs to realize the SPI data interface.





As with LVDS configuration mode, SPI configuration selection allows control of the number of active lanes. For SPI data interface configuration, the user has the option to configure single lane SPI or quad lane SPI.

## **SPI Active Data Lane Count**

The SPI can be configured to output the result data on either one or four data lanes, which is controlled by the SPI\_LVDS\_LANES bit in the [ADC](#page-82-0) Interface Configuration A register (see the ADC [Data Interface Configuration A Register](#page-82-0) section, Address 0x15). By default, this bit is set to 0 (one lane active), and can be set to 1 to use four data lanes. Note that this bit also sets the number of active data lanes for the LVDS interface. The data order and pin assignment to the serial data output (SDOx) pins is detailed in Table 23, and shown in [Figure 87.](#page-57-0)

#### *Table 23. SPI Data Lane(s) Data Order and Pin Assignment*



#### **Data Interface CRC**

To ensure the integrity of the result data, a CRC is appended to the FIFO results. This CRC is always enabled and appended. The computation of the result checksum is independent of that of the configuration interface. The result is 24 bits in length and is appended to each data result record acquired from the FIFO.

#### **Sign Extension**

When accessing the FIFO data with the SPI data interface, the 20-bit resolution of the AD4080 is not a convenient length for interfacing with microcontroller or microprocessor hosts. To make

*Table 24. GPIO Registers Overview*

<span id="page-50-0"></span>data access and storage simpler, the ADC result is sign extended to 24 bits. In this way, the data format aligns better with their selected host.

#### **GPIO PINS**

The AD4080 GPIO pins are intended to simplify the development of synchronous data acquisition applications by facilitating a simplified state control interface between the host processor, the data converter, and other related signal chain components. When configured as an output, these GPIO pins can be assigned as an indicator of device status, a digital control for a related signal chain component, or a serial data lane for device configuration. In input mode, the GPIO pins allow pin programming of converter features such as digital filter synchronization (reset) and an external event trigger.

The desired function for each GPIO is defined by writing to the GPIO Configuration A through GPIO Configuration C registers (Address 0x19 through Address 0x1B), see the [GPIO Configuration](#page-85-0) [A Register](#page-85-0) section through the [GPIO Configuration C Register](#page-87-0) section. The configuration for each GPIO includes an output enable bit, an output data bit, and a function selection. The output data bit determines the logical state of the output when the GPO data option is selected; otherwise, the output state is determined by the selected function, assuming the output is enabled. By default, GPIO0 is enabled as an output, and the configuration SPI SDO function is selected. All other GPIO outputs are disabled.

Table 25 provides a brief description of the available AD4080 GPIO functions. Each of the GPIO pins can be configured for any of the following functions.



#### *Table 25. GPIO\_x\_SEL Function Descriptions*



#### *Table 25. GPIO\_x\_SEL Function Descriptions (Continued)*



#### <span id="page-52-0"></span>**OVERVIEW**

The AD4080 includes several useful digital features that offer great solution benefits to many applications. These features can be individually enabled by the user, when required. A brief overview follows for these features, in depth explanation and definition of these features are found in the following sections.

- ► Event Detection: This feature allows the detection when the analog input has crossed user-configured thresholds. Such detections can be flagged in the configuration registers, output to a GPIO, or used to trigger the result FIFO.
- ► [Result FIFO](#page-54-0): This feature allows the acquisition of records of up to 16,384 conversion results into the on-chip memory. These acquisitions can be read back to the host controller via LVDS or the SPI data interface. The results stored in the FIFO can be either unprocessed ADC results or those that have been processed through the digital filter feature.
- ► [Digital Filter](#page-62-0): This feature offers three different digital filter configurations, each with a wide range of decimation rates, allowing oversampling benefits and the close control of the signal bandwidth.
- ► [System Error Correction Coefficients:](#page-69-0) Although the AD4080 offers excellent factory calibrated precision with minimal offset and gain errors, this feature allows the user to correct for signal chain that may be present within their application.

### **EVENT DETECTION**

The AD4080 includes an event detection feature, whereby the user can either indicate when a particular analog input threshold level

#### *Table 26. Event Detection*

is crossed or monitor a GPIO configured as an input. An internally generated event can then be used to set a flag in the configuration memory or routed to a configured GPIO output to be used to alert a host controller that a threshold condition is breached. It is also possible for a user to route an external signal to the AD4080 to be used as an external trigger. An internally or externally generated event can also be used to trigger the integrated result FIFO (see the [Result FIFO](#page-54-0) section). The mechanism for this is explained in the [Event Detection for FIFO](#page-54-0) section. The threshold detection compares a converted voltage code to a user-configured code because this is done in a sample by sample basis, and events immediately trigger, level hysteresis setting is also configurable to prevent unwanted triggering.



*Figure 81. Internally Generated Event Detection Signal Path*

The Figure 81 serves as an aid with detailing the configuration and operation of the event detection of the AD4080.



#### **Event Detection Timing**

When event detection is enabled in the general configuration register (see the [General Configuration Register](#page-88-0) section), the HI\_DTCT and LO\_DTCT signals indicate the occurrence of an internally generated event. These signals can be routed internally through the following paths:

- ► HI\_DTCT and LO\_DTCT are directly accessible via an enabled GPIO with GPIO x SEL set to 0b100 or 0b101, respectively, a threshold event can be monitored externally by a digital host via the GPIO. Logic 1 on a configured GPIO indicates detection of an event.
- ► HI\_DTCT and LO\_DTCT can each be routed by setting the HI\_ROUTE and LO\_ROUTE bits to 1, respectively, in the general configuration register (Address 0x1C) to allow HI\_DTCT and LO\_DTCT to propagate to the LO\_STATUS and HI\_STATUS bits in the device status register (see the [Device Status Register](#page-81-0) section, Address 0x14). These status bits can be monitored by the digital host via the configuration SPI. Logic 1 on a configured GPIO indicates the detection of an event. Each of these two bits are independently cleared when a 1 is written to these bits. Power cycling or device reset also result in the bits clearing.
- ► HI\_DTCT and LO\_DTCT can each be routed by setting the HI\_ROUTE and LO\_ROUTE bits to 1, respectively, in the general

configuration register (Address 0x1C) to allow HI\_DTCT and LO DTCT to propagate to the ALERT signal. Any enabled GPIO set to output a status alert, that is, with GPIO  $\times$  SEL set to 0b0110, routes the ALERT signal to the GPIO to indicate when an event occurs. A GPIO configured in this mode is normally high, with a logic low indicating that an event has occurred. As indicated in the [Figure 83](#page-54-0) section, this GPIO remains low only while the threshold level is crossed, and it returns to logic high as soon as the threshold bound is no longer crossed, and the timing in Figure 82 is satisfied.

Event detection is synchronous to the rising edge of the CNV+. A latency of two conversion clock cycles exists from the first CNV+ edge where the analog input crosses a threshold to a detected event that is flagged in the device status register and to any GPIO configured to route ALERT. As is evident in [Figure 81,](#page-52-0) where both the HI\_DTCT flag and ALERT routed to a GPIO are shown, the behavior, once the threshold level is no longer crossed, is different. When a CNV+ rising edge occurs where the analog input no longer crosses the set threshold, ALERT de-asserts two conversion cycles later, on the rising edge of CNV. Any HI\_DTCT or LO\_DTCT already set is not cleared at this point. These signals are only cleared by writing 1 to the relevant bits in the device status register (Address 0x14) or where a device reset occurred.



### <span id="page-54-0"></span>**Threshold Detect Levels**

The threshold detection of the AD4080 includes a hysteresis setting. By configuring this setting, the user can ensure that unwanted threshold triggering can be avoided. Figure 83 shows how this can be achieved. A single hysteresis setting is configured, that is then applied to both the HI\_THRESHOLD and LO\_THRESHOLD bits. The high and low detection flags remain set until the hysteresis thresholds are crossed.



#### **Enabling Event Detection**

By default, after power on or reset, HI\_ROUTE and LO\_ROUTE are set to Logic 0, masking the threshold level detection from generating any event alert. When enabled, the gated versions of these signals, HI\_DTCT\_GATED and LO\_DTCT\_GATED, are logic NOR'd to generate the ALERT signal. If a user requires the use of the HI\_DTCT, LO\_DTCT, or ALERT signals to flag an event occurrence externally, back to a digital host, the GPIO x SEL registers can be used to route any, or multiple, of these signals to the GPIO pins.

## **Event Detection for FIFO**

Event detection can also be used to arm the on-chip FIFO. The event detection for the FIFO can be triggered using either internal or external events as detailed in the [Table 26](#page-52-0) section.

To use the ALERT signal to trigger the FIFO, the HI\_ROUTE and/or the LO\_ROUTE bits must be configured as required, and the INT\_EVENT\_EN bit must be set to 1, to use a combined ALERT output to trigger the FIFO. Alternately, when configured with the INT\_EVENT\_EN bit set to 0, a GPIO EXT\_EVENT input must be configured, and this input triggers the FIFO when a Logic 1 is presented on the GPIO. Because this event was generated externally, there is no ALERT signal generated.

The HI\_THRESHOLD (Address 021 and Address 022) and LO THRESHOLD (Address 0x23 and Address 0x 24) bits can be used to configure the ADC output code thresholds for the internal event detection. These bits can each be masked using the HI\_ROUTE and LO\_ROUTE bits in the general configuration register (Address 0x1C). Setting these bits logic high, routes the bits to be used for the ALERT flag (that can be monitored using a preconfigured GPIO), it is also enabled as a FIFO event trigger as well as making these available as HI\_STATUS and LO\_STATUS flags in the device status register (Address 0x14).



*Figure 84. FIFO Event Detection Logic*

#### **Event Detection ADC Data Result**

The ADC data result, as shown in [Figure 81](#page-52-0), is dependent of the selected data path. As is evident in [Figure 95,](#page-62-0) where the digital filter (see the [Digital Filter](#page-62-0) section) is enabled, the output of the selected filter refers to the ADC data result that is checked by the threshold detection for event detection.

## **RESULT FIFO**

A single port data FIFO was integrated into the AD4080 for applications where a reduced data interface transmission load is required and where asynchronous data capture and access is appropriate. This FIFO can serve to reduce the requirements for the digital host controller and can, for example, enable the AD4080 to be deployed in systems using an MCU digital host. The data FIFO allows for a record of up to 16,384 data results to be captured per acquisition burst without result loss due to data overflow. As a single port memory, simultaneous data interface read and ADC conversion result write operations are not permitted to the FIFO.

To allow synchronization of FIFO access between the host controller and ADC, status flags are included to indicate if the memory is full (FIFO\_FULL) or if no new data available in the FIFO (FIFO READ DONE), that is, there is no new data since the last trigger was set, or the last FIFO data read back of a result record has already been completed. When  $N = WATERMARK$  is reached, that is, when the conversion result corresponding to the specified count in the FIFO\_WATERMARK register is loaded into the data FIFO, memory is set as full, and the FIFO\_FULL bit gets asserted in device status register (see the [Device Status Register](#page-81-0) section, Address 0x4). The status bits can be accessed by reading directly from the device status register (Address 0x14) via the configuration SPI, appending the status to the data SPI frame, or by assigning the desired status flags to a GPIO pin by setting the required GPIO x SEL bit. Further details on these GPIO can be found in the [GPIO Pins](#page-50-0) section. The user can also select between various modes of initiating the burst acquisition, which will be described further in the [FIFO Mode Selection and Configuration](#page-55-0) section.

# <span id="page-55-0"></span>**FIFO Mode Selection and Configuration**

There are four distinct modes in which the data FIFO of the AD4080 can be configured. The active mode is selected by setting the FIFO\_MODE bits in the general configuration register (see the [General Configuration Register](#page-88-0) section, Address 0x1C). By default,

the FIFO is disabled (FIFO\_MODE = 00). The modes are designed to fit the use case requirements of different applications., Table 27 provides details about each FIFO mode and their applicable use cases.



#### *Table 27. FIFO Configuration Modes (FIFO\_MODE)*

#### **FIFO Event Detection**

The FIFO is configured for capture in event detection mode (FIFO\_MODE = 10 or FIFO\_MODE = 11, the following event detection options (see the [Table 26](#page-52-0) section) are available.

The general configuration register (Address 0x1C) contains the internal event enable bit (INT\_EVENT\_EN) which determines whether the AD4080 FIFO is to respond to an external or internal event trigger. The default state of this bit on power on and reset is INT EVENT  $EN = 0$ , which is configured for an external event.

## **Asynchronous Data Capture**

To use the FIFO for asynchronous capture, first write to the FIFO watermark register (see the [FIFO Watermark Register](#page-89-0) section, Address 0x1D) with the number of conversions to be captured in each burst; any integer between 1 and 16,384 can be entered. If using GPIO to pass the FIFO status bits to the host controller, program those selections into the GPIO configuration registers prior to initiating the capture. Refer to the [GPIO Pins](#page-50-0) sections for further detail on GPIO configuration.

The final steps in initiating an asynchronous capture into the data FIFO include enabling the FIFO and then starting the conversion

clock. To enable the data FIFO in the general configuration register (see the [General Configuration Register](#page-88-0) section, Address 0x1C), the FIFO\_MODE bits must be set to immediate trigger mode (01). In this mode, the FIFO stores the results of the most recent FIFO\_WATERMARK samples and then automatically disables capture into the memory. The results can then be accessed through the SPI data interface or LVDS interface.

When the FIFO is enabled, each conversion result is loaded into the internal memory on the rising edge of the convert start signal, CNV. Internal timing dictates that FIFO\_WATERMARK + three conversion clocks are required to write FIFO\_WATERMARK sample results into the FIFO memory. See [Figure 86](#page-57-0) and [Figure 87](#page-57-0) for additional information.

The Figure 85 timing diagram shows an example where FIFO WA-TERMARK is set to 1000, and the first ADC results after the event occurred is captured by the FIFO after the third CNV. After  $N = 1000$ , that is, it has reached the FIFO\_WATERMARK value, FIFO\_FULL is asserted, and data stops being captured into the FIFO.



*Figure 85. FIFO Data Capture Example, WATERMARK = 1000*

#### <span id="page-57-0"></span>**Asynchronous Read Access**

Access to the FIFO data is made through either a LVDS configuration (single lane only) or the multioutput SPI configuration of the data interface after the capture has completed. As a result, access is asynchronous to the capture process, and there are no specific timing restrictions between the conversion and interface clocks. Synchronization between the data FIFO and the data interface clock domain requires each read access to begin with a header

followed by a transfer of M bytes of conversion data; where M equals the product of the total number of results specified in the FIFO\_WATERMARK register (Address 0x1D and Address 0x1E) and the integer length in bytes (for SPI data interface) of a single conversion result. Note that the number of active data lanes reduces the access period by a factor of 2 for each doubling of the number of active lanes.



*Figure 86. Asynchronous Capture Read Timing, Data FIFO Enabled, Single Data Lane*







*Figure 88. Asynchronous Capture Read Timing, Data FIFO Enabled, LVDS Configuration*

## **FIFO Timing Considerations**

#### **Immediate Trigger Mode**

[Figure 90](#page-59-0) illustrates the timing relationship between the command to arm the FIFO for data write access and the point at which the FIFO is armed. [Figure 90](#page-59-0) shows an example of where single lane SPI data access is configured and FIFO\_FULL and FIFO\_READ\_DONE are output to GPIO. Because a capture has not yet been initiated, FIFO\_FULL and FIFO\_READ\_DONE are driven low. A free running CNV clock is shown in this example. Upon receipt of the update to the general configuration register (Address 0x1C), the FIFO controller advances to an idle state

on the next rising edge of CNV. The FIFO then advances to the writing state after two further CNV clock edges and begins filling the FIFO until WATERMARK results are loaded and FIFO\_FULL is generated.

Upon completion of reading the FIFO data, a rearming event for immediate mode capture involves disabling the FIFO by writing 00 to FIFO\_MODE then re-enabling by writing 01 to the FIFO mode to arm the FIFO for a new capture. As is the case with the initial arming, the FIFO advances to the idle state upon receipt of the first rising edge of CNV after the configure instruction to arm the FIFO is issued. The sequence and timing is the same as for the initial FIFO arming. See [Figure 90.](#page-59-0)



*Figure 89. Immediate Trigger ModeArming*

<span id="page-59-0"></span>

*Figure 90. Immediate Trigger Mode Rearming*

#### **Event Triggered Capture, Read Latest WATERMARK**

Event triggered (read latest) mode is used where there is interest only in the ADC data after an event occurs. This event can be an internally generated event, where the AD4080 is running continuously, and the threshold detection is enabled to trigger an event as soon as an ADC input threshold is crossed. Or, the user can be independently monitoring the system or ADC input for an event, and an external event trigger is user-issued via a configured GPIO.

As in all cases of arming the FIFO, the first rising edge after a FIFO MODE write command arms the FIFO for data capture; however, no data is written to the FIFO until an event of the selected method occurs.

Rearming the trigger involves a similar process to the immediate mode rearming. The FIFO is firstly disabled by writing 00 to the FIFO MODE bits before, and then rearmed by again enabling the required capture mode.



*Figure 91. Event Triggered Capture, Read Latest WATERMARK Arming*

### <span id="page-61-0"></span>**Event Trigger Capture Mode, Read All FIFO**

Event triggered mode can be used where ADC results immediately prior to the event, as well as those after, are of interest to the user. Once armed, the FIFO continuously fills with new ADC results, storing up to, at most, 16,384 of the most recent results, wrapping around and overwriting the oldest results in FIFO memory once 16,384 captures are made.

Once a trigger event occurs, the FIFO continues to capture WA-TERMARK number of results after the event. Only multiples of four are valid values to set the FIFO\_WATERMARK register when using this mode. After an event has occurred, and the WATERMARK number of results has been captured in the FIFO, no further new results are captured until the FIFO is rearmed. The user must read back all 16,384 FIFO results, and the value set for FIFO\_WATER-MARK allows the user to determine where in the FIFO result data that the event occurred and also to distinguish between results that occurred before the event and those which occurred after the event as shown in Figure 93 and Figure 92. In the full FIFO read back, the first result after the event triggered is located at 16384 − (FIFO\_WATERMARK − 1), where FIFO\_WATERMARK is the value set prior to arming the capture. If this capture mode is armed and an event occurs before the FIFO wraps around once, the FIFO results before the event contain either results from previous FIFO use or, when used for the first time after power cycling the device, the FIFO contains random data in the FIFO data locations before the event.



FIFO WATERMARK WAS SET TO 8192





*Figure 93. FIFO Event Capture Mode Read All FIFO Mode Example, Locating Event Position in FIFO*



*Figure 94. Event Trigger Capture Mode, Read All FIFO Rearming*

#### <span id="page-62-0"></span>**DIGITAL FILTER**

The AD4080 includes the option of enabling an integrated digital filter for applications where noise rejection by bandwidth limiting is desired. As shown in Figure 95 and detailed as follows, there are four paths available by which to route digital data: no digital filtering, a sinc1 filter, a sinc5 filter, or a sinc5 compensated filter.

Further details on each of these filters is described in the following sections. To ensure the first filter result produces the correct data, when a user makes a change to the filter selection, a reset must be issued via the GPIO pin configured for filter synchronization (FILTER\_SYNC).



*Figure 95. Digital Filter Selection Options*

## **Benefits of Digital Filtering**

The ADC result path can be configured to use the integrated digital filter feature. The filter configuration register (see the [Filter Configu](#page-92-0)[ration Register](#page-92-0) section, Address 0x29) contains the FILTER SEL bits that allow the user to bypass (default register setting) the digital filter or select from one of three filter options. Each filter has unique bandwidth profile properties, which allows high flexibility in allowing selection to be made depending on the end application requirements. Table 28 shows the −3 dB bandwidths achievable for each user-selectable filter type. The SINC\_DEC\_RATE bits controls the bandwidth and the data decimation factor.

These filters allow the user to programmatically control the noise bandwidth of their signal chain and also can offer benefits by reducing the amount filtering required in the analog front end, while offering dynamic range improvement without the need for additional components. The digital filter response sections have addition details on the different filter profiles that include the following:

- ► Sinc1 has a wider bandwidth but is not optimized for pass-band flatness.
- ► Sinc5 has a flatter pass-band response; however, with a reduced bandwidth.
- $\triangleright$  Sinc5 + compensation is a filter highly optimized to give excellent pass-band flatness with a ripple within ±0.1 dB.



*Table 28. Filter Bandwidth*

#### *Table 28. Filter Bandwidth (Continued)*



#### <span id="page-64-0"></span>**Filter Decimation Configuration**

Configuration of the digital filter is done through the filter configuration register (see the [Filter Configuration Register](#page-92-0) section, Address 0x29). The FILTER SEL bits select the active filtering path (that is, what filters are active), with each path having different allowed decimation rates (see Table 29).



**FILTER\_SEL** output shift register. The user must ensure that the same LVDS **Bits Value Active Filter Allowed Decimation Rates** 0b00 | No filtering (default) | No decimation the repeated result data, which is shown in Figure 96, where a 0b01 SINC1 filter 2, 4, 8, 16, 32, 64, 128, 256, decimate by 4 example is used. 512, 1024 0b10 | SINC5 filter | 2, 4, 8, 16, 32, 64, 128, 256 0b11 | SINC5 + compensation filter | 4, 8, 16, 32, 64, 128, 256, 512  $CM$ ADC\_DATA [19:0] 0xXXXXXh ADC\_RESULT\_1 ADC\_RESULT\_2 ADC\_RESULT\_3 ADC\_RESULT\_4 ADC\_RESULT\_5 ADC\_RESULT\_6 ADC\_RESULT\_7h ADC\_RESULT\_8 ADC\_RESULT\_9 STATUS (INTERNAL) { FILTER\_COUNT xx  $\overline{\mathbf{c}}$  $\overline{4}$ 3 FILTER\_READY **INTERFACE** OUTPUT\_DATA [19:0] 0xXXXXXh 0xXXXXXI 0xXXXXXh 0xXXXXXh 0xXXXXXI FILTER\_RESULT\_1 FILTER\_RESULT\_1 FILTER\_RESULT\_1 FILTER\_RESULT\_1 FILTER\_RESULT\_2

*Figure 96. Digital Filter Decimate by 4 Frame Overview*

The decimation factor is set via the SINC\_DEC\_RATE bits in the filter configuration register (see [Table 62](#page-92-0) for the encoding).

The readiness of new filter data can be indicated to the host controller via a GPIO pin by setting one of GPIO x SEL bits in either GPIO Configuration B register (see the [GPIO Configuration B](#page-86-0) [Register](#page-86-0) section, Address 0x1A) or GPIO Configuration C register (see the [GPIO Configuration C Register](#page-87-0) section, Address 0x1B) to 0011 (filter result ready (active low)). Until new data is available to the interface, the data from the previous result remains in the clock rate is maintained, and the user can either reread or disregard

#### **Filter Reset Conditions**

#### **Direct LVDS**

When accessing the filtered data directly via the LVDS interface, the AD4080 resets the filter by the following two methods:

- ► By configuring the filter, by issuing a write to the filter configuration register, Bits[7:0] (see the [Filter Configuration Register](#page-92-0) section, Address 0x29).
- ► By asserting a GPIO that' is configured for FILTER SYNC operation.

#### **With FIFO**

When the FIFO is enabled, the user must use a GPIO configured as FILTER\_SYNC to reset the filter for each FIFO acquisition.

### **Filter Synchronization**

Set GPIO x SEL to FILTER\_SYNC to configure this input providing synchronization to the controller of the user, which can be used to synchronize the filters across multiple AD4080 devices. The FILTER\_SYNC signal timing requirements for a filter reset are shown in Figure 97.



*Figure 97. Filter Reset Timing*

#### **Filter Result Ready Indicator**

Setting the GPIO x SEL bits to 0011 configures the GPIO to output the FILTER\_RESULT\_RDY signal, which is an active low logic signal that indicates to the host controller when each new filter result is complete. When LVDS is used to directly read out the filter results, this indicator can alert the user when each new filtered conversion result is available to read via the interface.

#### **Filter Interface Timing Considerations**

Continuous access to filtered data results is available only through the LVDS data interface. SPI data interface access to filtered results is only made via the FIFO. The timing considerations, in this case, are described in the Filter Interface Timing Considerations when Using the FIFO section. For use with the LVDS data interface, it is recommended to use a GPIO, configured with the appropriate GPIO x SEL (0011) to output the filter result ready (active low) signal, as is shown in the example [Figure 96](#page-64-0) timing diagram.

#### **Filter Interface Timing Considerations when Using the FIFO**

Figure 98 serves as an example to illustrate the sequence of events in this mode of operation. This example illustrates a sinc1 filter with

a decimate by 2 setting, where three results (that is, WATERMARK = 3) are configured to be stored in the FIFO. When using the integrated digital filters with the FIFO, the filter must be reset prior to each FIFO acquisition record. This reset must be given on the first CNV rising edge, where the FILTER SYNC signal must be brought low at least 15 ns prior to the CNV edge and then released at least 5 ns before the next rising edge. The first ADC result is ready  $t_{\text{MSB}}$  after the second CNV rising edge. This first ADC result is latched into the filter on the third CNV rising edge. The fourth CNV rising edge latches the second ADC result into the digital filter. On the fifth rising edge, the first decimate by 2 result is complete, which is indicated by the FILTER\_READY signal going active on the fifth rising edge. This first filtered result is loaded into the FIFO on the sixth CNV rising edge. Because this example uses WATERMARK = 3, when three filtered (that is, six core ADC results, decimated by 2) results are loaded to the FIFO, the WATERMARK is reached, and FIFO\_FULL is asserted to indicate to the user that a FIFO record is available to read via the configured data interface (that is, the LVDS data lane(s) of the SPI data lane(s)). To initiate a subsequent FIFO record acquisition of the filtered ADC results, the user must start the whole sequence over, beginning again with the reset of the digital filter by bringing the FILTER SYNC signal low on the first rising edge of CNV.



# **Digital Filter Conversion Pulses**

The total number of CNV pulses required for a single filter decimated result (sinc1 settling clocks) can be calculated using the following formula:

Settling CNV Pulses<sub>SINC1</sub> =  $2 + (D + 1)$ 

Note that each of the three filter types has a unique formula to determine the number of clocks required.

For the sinc5 settling clocks, the equation is as follows:

Settling CNV Pulses<sub>SINC5</sub> =  $2 + (5 \times D + 4)$ 

For the sinc5 with compensation settling clocks, the equation is as follows:

Settling CNV Pulses $_{SINCS + COMP}$  =  $2 + (35 \times D + 10)$ 

Where D equals the decimation rate 2, 4, 8 …

# **Digital Filtering Settling Time**

The settling time for the selected filter is the number of settling clocks times  $t_{\text{CONV}}$ , as follows:

Filter Settling Time = (Settling CNV Pulses $_{FILTERTYPE}$ )  $\times t_{CONV}$ 

# **Digital Filtering Settling Time when Using FIFO**

When using the FIFO with filtered data, it is important to note that each new FIFO record of results must begin by issuing a FILTER\_SYNC signal on the first CNV to reset and initialize the filter and to prevent unflushed data from being contained in the first FIFO record result.

The minimum total number of conversion pulses required to fill a full FIFO record can be calculated as follows:

Total Required CNVs =  $(D \times WATERMARK) +$ Settling CNV PulsesFILTERTYPE

Where D equals the decimation rate 2, 4, 8 …

# **Digital Filter Response**

# **Sinc1 Filter**



*Figure 99. Sinc1 Filter Response, Decimate by 2*



*Figure 100. Sinc1 Filter Response, Decimate by 4*



*Figure 101. Sinc1 Filter Response, Decimate by 8*



*Figure 102. Sinc1 Filter Response, All Decimation Rates*





*Figure 103. Sinc5 Filter Response, All Decimation Rates*





*Figure 104. Sinc5 + Compensation Filter Response, Decimate by 2*



*Figure 105. Sinc5 + Compensation Filter Response, Decimate by 2, Pass-Band Ripple*



*Figure 106. Sinc5 + Compensation Filter Response*

#### <span id="page-69-0"></span>**SYSTEM ERROR CORRECTION COEFFICIENTS**

Systematic gain and offset errors exist in all practical data acquisition circuits, and thus, the need for correction is essential to maximize the precision of the measurement channel. While these quantities can be corrected for in the host processor, implementation can be inefficient and consume more power than if integrated within the data converter. To minimize these challenges for the end user, the AD4080 has integrated both gain and offset correction on a per sample basis.

To describe the available error corrections, consider that the transfer function of an ideal ADC can be described by the straight line equation.

*y* = *mx* + *c* (2)

This equation can be applied to the ADC transfer function where: *y* is the corrected ADC result. *m* is the gain or slope of the line. *x* is the uncorrected ADC result. *c* is the offset.

The gain or slop of the line can be described as follows:

*m* = (*y2* − *y1*)/(*x2* − *x1*)

where the following are in volts:

y2 is the input voltage at close to the positive full-scale input. y1 is the input voltage at close to the negative full-scale input. x2 is the converted voltage with the y2 voltage applied at the input. x1 is the converted voltage with the y1 voltage applied at the input.

The ideal slope or gain is  $m = 1$  V/V

The system error correction coefficients in the Offset Error Correction and Gain Error Correction sections detail how signal chain errors in offset (c) and gain (m) can be corrected using the configuration registers of the AD4080.

# **Offset Error Correction**

The AD4080 is factory calibrated to give low zero error. To account for system offset errors that may be present in a users application signal chain, an offset error correction function was included, which allows users to correct for system offsets in their application by applying a code to the OFFSET bit field in the offset Register at Address 0x24 and Address 0x25, Bits[11:0]. This bit field is a 12-bit value in a twos compliment data format.

The bit field is a 12-bit value in a twos compliment data format and OFFSET LSB represents the value of the ADC LSB as defined in the [Transfer Function](#page-18-0) section. The range of offset error correction is therefore defined as −2048 × LSB (0x800) to +2047 × LSB (0x7FF). This represents a voltage range of ±11.71 mV for the specified  $V_{RFFIN}$  = 3.0 V. The default value for this register, after power on, or after a software reset, is 0x000, which represents the zero offset correction applied.

# **Gain Error Correction**

The AD4080 is a high precision ADC with factory calibrated, gain error correction. To allow a user to correct for any signal chain gain error within their application, the GAIN register (see the [Gain](#page-91-0) [Correction Register](#page-91-0), Address 0x27 and Address 0x28) can be used. The GAIN bit field is a 10-bit value that allows a nominal gain error correction of ±1.5594% of full scale. The 10-bit register is coded in a straight binary data format, where the default value after power on, or software reset, is 0x200. This value represents no gain error correction being applied to the ADC results.

With the GAIN register first set to the default 0x200 value, the user can perform a two-point voltage measurement, preferably close to positive and negative full-scale inputs, and use the slope or gain equation in the System Error Correction Coefficients section to determine their system gain error. This system error can then be adjusted with a resolution of 1.5594%/512 = 0.00305%. The required correction calculated can be input to the GAIN register.

# <span id="page-70-0"></span>**LAYOUT GUIDELINES**

The AD4080 includes all critical bypass capacitors within the device package, which greatly reduces the layout challenge for a precision, high-speed converter. These integrated capacitors are optimally placed within the device package to ensure that maximum performance is easily obtained. However, as with any precision mixed signal device, care must be taken in system device placement to ensure that there is proper partitioning of the critical analog signal chain component routing and routing of the high-speed digital signals to prevent unwanted coupling effects.

Note the following layout considerations:

- ► The AD4080 contains internal decoupling on all power supplies, AVDD33 (0.47 μF), VDD11 (1.88 μF), IOVDD (0.22 μF), as well as VDDLDO (0.22 μF). Therefore, no external bypass capacitors are required, saving board space and reducing bill of material (BOM) count and sensitivity.
- ► Ensure good partitioning of analog and digital domain signals within the design by, for example, having all analog signals in

from the left-hand side and keeping dynamic digital signals on the right-hand side.

- ► Have a solid ground plane under the AD4080 and connect all analog ground (GND) pins, reference ground (REFGND), and digital ground (IOGND) pins to this shared plane.
- ► Recommended connections of ground (GND), reference ground (REFGND), and digital ground (IOGND) connections are shown in Figure 107. It is recommended to not keep the current return path of the reference IC in the same current loop as the current return loop from the other circuitry on the PCB. Connect the reference local star point to the ADC star point ground on the top layer of the PCB as shown in Figure 107.
- ► See Figure 108 for the side view cross-section of the PCB board showing the ground planes distribution . Note that Figure 108 only shows the ground planes but does not including the signal tracks.



*Figure 107. AD4080 External Reference Ground Connections*



*Figure 108. Recommended PCB Ground Planes Layout*

### **CONFIGURATION REGISTERS**

The features of the AD4080 family have been designed to simplify the application of low latency data capture to a broad array of measurement applications. This simplification is achieved through customization of the data interface, data path, and data access method to satisfy both measurement and the host processor interface requirements via the available configuration registers.

The register space was organized in contiguous regions by function to streamline device configuration as described in Table 30. As a result, the interface streaming functions (see [Instruction Mode](#page-33-0) [Selection\)](#page-33-0) can be leveraged to simplify device configuration to a single SPI frame consisting of an instruction word and associated

data. For most applications, modifications to the register space address range of Address 0x15 to Address 0x29 are sufficient. Modification of content in the configuration interface and product ID space (Address 0x00 to Address 0x11) is only necessary to initiate a software reset or to change the configuration access method. Note that changes to the configuration access method are outside the scope of this document. For assistance with these options, contact your [local Analog Devices sales representative](https://www.analog.com/en/support/find-sale-office-distributor.html) or submit a request for technical assistance through the **Precision ADCs** page on the *ADI Engineer Zone* at [https://ez.analog.com/data\\_con](https://ez.analog.com/data_converters/precision_adcs/)[verters/precision\\_adcs/.](https://ez.analog.com/data_converters/precision_adcs/)

#### *Table 30. Register Map Organization*



#### *Table 31. Configuration Register Summary—Configuration Interface Functions (Address 0x00 to Address 0x11)*






## **REGISTER DETAILS**

## **Interface Configuration A Register**

**Address: 0x00, Reset: 0x10, Name: INTERFACE\_CONFIG\_A**



#### *Figure 109. Interface Configuration A Settings*

#### *Table 32. Bit Descriptions for INTERFACE\_CONFIG\_A*



## **Interface Configuration B Register**

### **Address: 0x01, Reset: 0x00, Name: INTERFACE\_CONFIG\_B**



#### *Figure 110. Additional Interface Configuration B Settings*

### *Table 33. Bit Descriptions for INTERFACE\_CONFIG\_B*



### **Device Configuration Register**

## **Address: 0x02, Reset: 0x00, Name: DEVICE\_CONFIG**



#### *Figure 111. Device Configuration Register*

### *Table 34. Bit Descriptions for DEVICE\_CONFIG*



## **Chip Type Register**

### **Address: 0x03, Reset: 0x07, Name: CHIP\_TYPE**

The chip type is used to identify the family of Analog Devices devices a given device belongs to. CHIP\_TYPE must be used in conjunction with the Product ID to uniquely identify a given product.





### *Table 35. Bit Descriptions for CHIP\_TYPE*



## **Product ID Low Register**

### **Address: 0x04, Reset: 0x00, Name: PRODUCT\_ID\_L**

This register is the low byte of the Product ID.



Product Identification.

### *Figure 113. Product ID Low Register*

### *Table 36. Bit Descriptions for PRODUCT\_ID\_L*



## **Product ID High Register**

**Address: 0x05, Reset: 0x00, Name: PRODUCT\_ID\_H**

This register is the high byte of the Product ID.



Product Identification.

### *Figure 114. Product ID High Register*

### *Table 37. Bit Descriptions for PRODUCT\_ID\_H*



## **Chip Grade Register**

### **Address: 0x06, Reset: 0x02, Name: CHIP\_GRADE**

This register identifies product variations and device revisions.



#### *Figure 115. Chip Grade Register*

#### *Table 38. Bit Descriptions for CHIP\_GRADE*



## **Scratch Pad Register**

### **Address: 0x0A, Reset: 0x00, Name: SCRATCH\_PAD**

This register can be used to test writes and reads.



### *Figure 116. Scratch Pad Register*

### *Table 39. Bit Descriptions for SCRATCH\_PAD*



## **SPI Revision Register**

### **Address: 0x0B, Reset: 0x83, Name: SPI\_REVISION**

This register indicates the SPI revision.



### *Figure 117. SPI Revision Register*

### *Table 40. Bit Descriptions for SPI\_REVISION*



## **Vendor ID Low Register**

## **Address: 0x0C, Reset: 0x56, Name: VENDOR\_L**

This register is the low byte of the Vendor ID.



 $[7:0]$  VID[7:0] (R) -

Analog Devices Vendor ID

*Figure 118. Vendor ID Low Register*

#### *Table 41. Bit Descriptions for VENDOR\_L*



## **Vendor ID High Register**

## **Address: 0x0D, Reset: 0x04, Name: VENDOR\_H**

This register is the high byte of the Vendor ID.



#### *Figure 119. Vendor ID High Register*

#### *Table 42. Bit Descriptions for VENDOR\_H*



### **Stream Mode Register**

### **Address: 0x0E, Reset: 0x00, Name: STREAM\_MODE**

This mode is not supported.



Stream Mode Loop Counter

#### *Figure 120. Stream Mode Register*

### *Table 43. Bit Descriptions for STREAM\_MODE*



## **Transfer Configuration Register**

## **Address: 0x0F, Reset: 0x00, Name: TRANSFER\_CONFIG**

This register controls how data moves between the controller and the target registers.



#### *Figure 121. Transfer Configuration Register*

#### *Table 44. Bit Descriptions for TRANSFER\_CONFIG*



# **Interface Configuration C Register**

## **Address: 0x10, Reset: 0x23, Name: INTERFACE\_CONFIG\_C**

This register contains additional interface configuration settings.







### *Table 45. Bit Descriptions for INTERFACE\_CONFIG\_C*

## **Interface Status A Register**

## **Address: 0x11, Reset: 0x00, Name: INTERFACE\_STATUS\_A**

Status bits are set to 1 to indicate an active condition. These bits can be cleared by writing a 1 to the corresponding bit location.



#### *Figure 123. Interface Status A Register*

#### *Table 46. Bit Descriptions for INTERFACE\_STATUS\_A*



## **Device Status Register**

## **Address: 0x14, Reset: 0x09, Name: DEVICE\_STATUS**



*Figure 124. Device Status Register*





# **ADC Data Interface Configuration A Register**

## **Address: 0x15, Reset: 0x40, Name: ADC\_DATA\_INTF\_CONFIG\_A**









## **ADC Data Interface Configuration B Register**

## **Address: 0x16, Reset: 0x00, Name: ADC\_DATA\_INTF\_CONFIG\_B**



#### *Figure 126. ADC Data Interface Configuration B Register*

#### *Table 49. Bit Descriptions for ADC\_DATA\_INTF\_CONFIG\_B*



### **ADC Data Interface Configuration C Register**

### **Address: 0x17, Reset: 0x20, Name: ADC\_DATA\_INTF\_CONFIG\_C**



#### *Figure 127. ADC Data Interface Configuration C Register*

## *Table 50. Bit Descriptions for ADC\_DATA\_INTF\_CONFIG\_C*



### *Table 50. Bit Descriptions for ADC\_DATA\_INTF\_CONFIG\_C (Continued)*



## **Power Control Register**

## **Address: 0x18, Reset: 0x00, Name: PWR\_CTRL**

It is not recommended to write to this register.



#### *Figure 128. Power Control Register*

### *Table 51. Bit Descriptions for PWR\_CTRL*



## **GPIO Configuration A Register**

## **Address: 0x19, Reset: 0x01, Name: GPIO\_CONFIG\_A**



*Figure 129. GPIO Configuration A Register*





# **GPIO Configuration B Register**

**Address: 0x1A, Reset: 0x00, Name: GPIO\_CONFIG\_B**



*Figure 130. GPIO Configuration B Register*

### *Table 53. Bit Descriptions for GPIO\_CONFIG\_B*



# **GPIO Configuration C Register**

**Address: 0x1B, Reset: 0x00, Name: GPIO\_CONFIG\_C**



*Figure 131. GPIO Configuration C Register*

### *Table 54. Bit Descriptions for GPIO\_CONFIG\_C*



# **General Configuration Register**

## **Address: 0x1C, Reset: 0x00, Name: GENERAL\_CONFIG**



### *Figure 132. General Configuration Register*

#### *Table 55. Bit Descriptions for GENERAL\_CONFIG*



### **FIFO Watermark Register**

### **Address: 0x1D and Address: 0x1E, Reset: 0x4000, Name: FIFO\_WATERMARK**

This is the watermark value. If the user writes a value <1, it is clipped at 1. If >16,384, clipped at 16,384.



### *Figure 133. FIFO Watermark Register*

### *Table 56. Bit Descriptions for FIFO\_WATERMARK*



## **Event Detection Hysteresis Configuration Register**

## **Address: 0x20 and Address: 0x1F, Reset: 0x0000, Name: EVENT\_HYSTERESIS**



#### *Figure 134. Event Detection Hysteresis Configuration Register*

#### *Table 57. Bit Descriptions for EVENT\_HYSTERESIS*



## **Event Detection High Threshold Configuration Register**

**Address: 0x21 and Address: 0x22, Reset: 0x0000, Name: EVENT\_DETECTION\_HI**



### *Figure 135. Event Detection High Threshold Configuration Register*

### *Table 58. Bit Descriptions for EVENT\_DETECTION\_HI*



## **Event Detection Low Threshold Configuration Register**

### **Address: 0x23 and Address: 0x24, Reset: 0x0000, Name: EVENT\_DETECTION\_LO**



#### *Figure 136. Event Detection Low Threshold Configuration Register*

### *Table 59. Bit Descriptions for EVENT\_DETECTION\_LO*



### **Offset Correction Register**

### **Address: 0x25 and Address: 0x26, Reset: 0x0000, Name: OFFSET**



#### *Figure 137. Offset Correction Register*

#### *Table 60. Bit Descriptions for OFFSET*



# **Gain Correction Register**

## **Address: 0x27 and Address: 0x28, Reset: 0x0200, Name: GAIN**



*Figure 138. Gain Correction Register*

### *Table 61. Bit Descriptions for GAIN*



# **Filter Configuration Register**

## **Address: 0x29, Reset: 0x00, Name: FILTER\_CONFIG**



### *Figure 139. Filter Configuration Register*

### *Table 62. Bit Descriptions for FILTER\_CONFIG*



# **OUTLINE DIMENSIONS**



For the latest package outline information and land patterns (footprints), go to [Package Index.](https://www.analog.com/en/resources/packaging-quality-symbols-footprints/package-index.html)

Updated: February 29, 2024

# **ORDERING GUIDE**



 $1 Z =$  RoHS Compliant Part.

## **EVALUATION BOARDS**



<sup>1</sup> Z = RoHS-Compliant Part.

